放射光実験、XAFSとその周辺

-これからXAFSを始める人のために-

阿部 仁 (KEK-PF)

hitoshi.abe@kek.jp

Outline

- 放射光
- 軟X線領域のXAFS: NEXAFS, XMCD
- 蛍光X線分析 (XRF, XFA)
- （硬X線領域の）XAFS
  - 原子間距離を求める、“長さを測る”、ことについて
  - EXAFSの式、それを得るまでの理論的概念の整理
  - XAFS測定
- Some topics

放射光（Synchrotron Radiation）

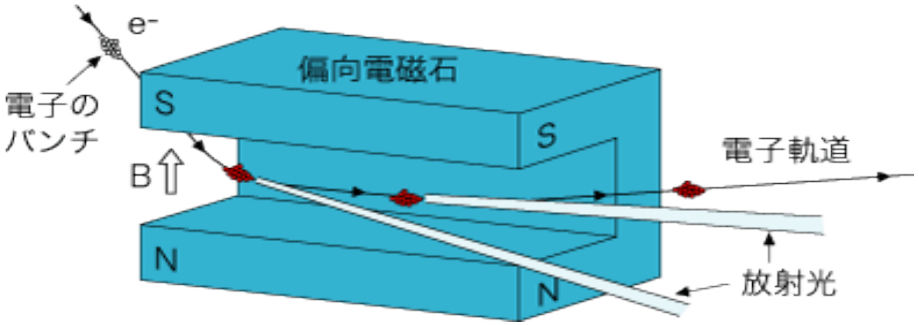
高エネルギーの電子が磁場の中を運動

└ 偏向電磁石（Bending Magnet）,etc.

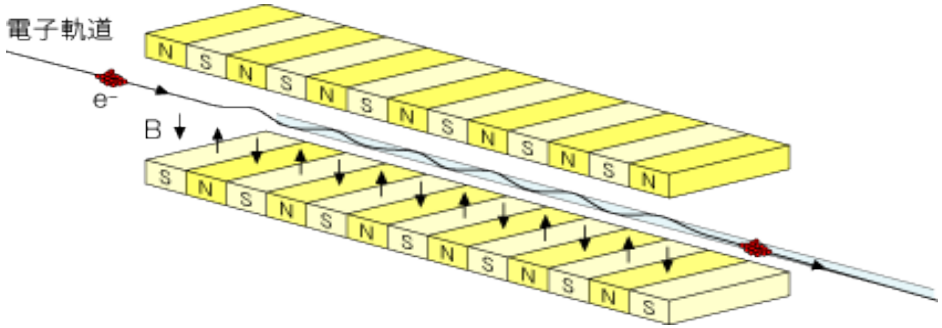
電子：円運動の中心に向かって力を受け，軌道が曲げられる

↓

電磁波が円軌道の接線方向に放射される；放射光

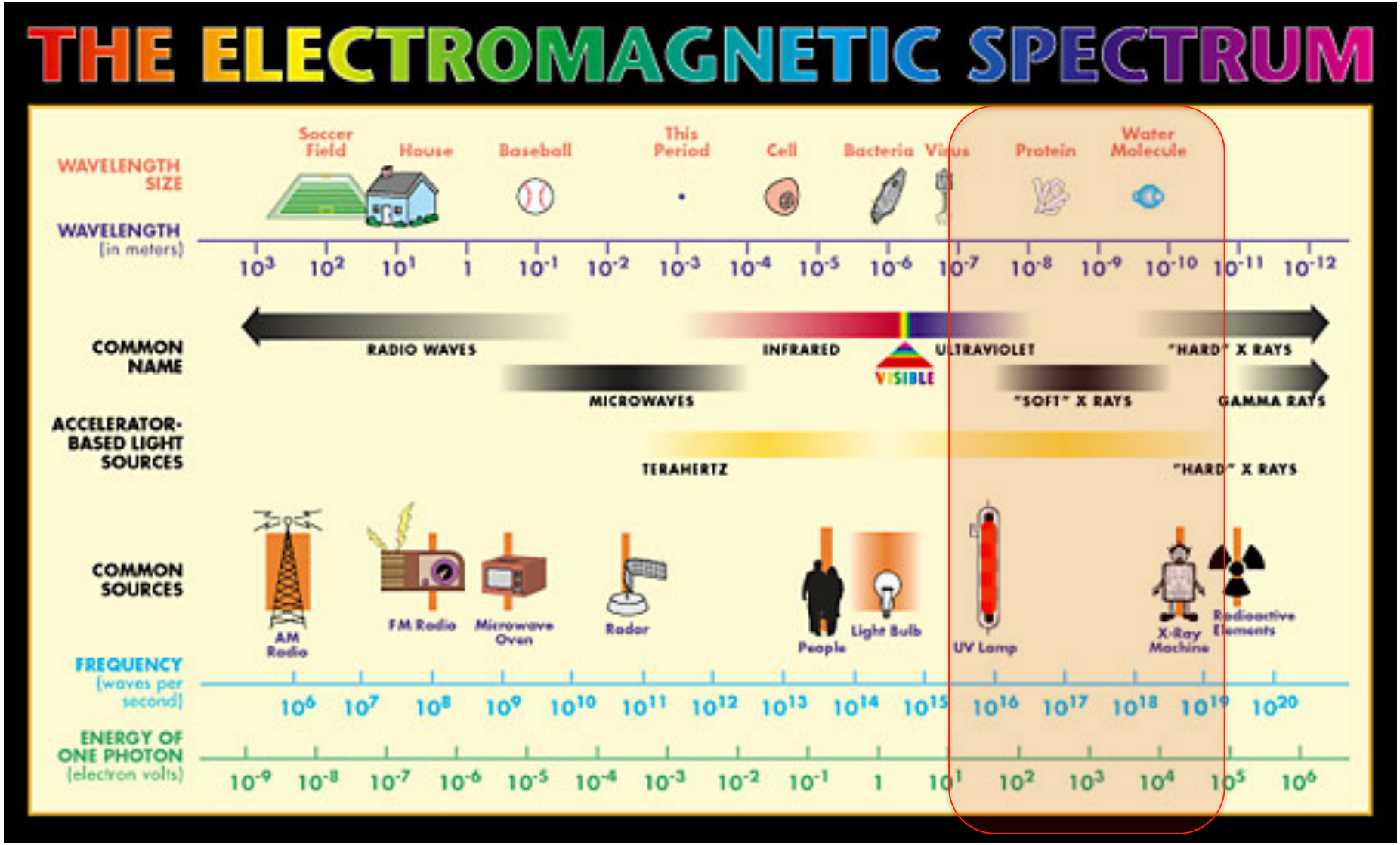


偏向電磁石（Bending Magnet）

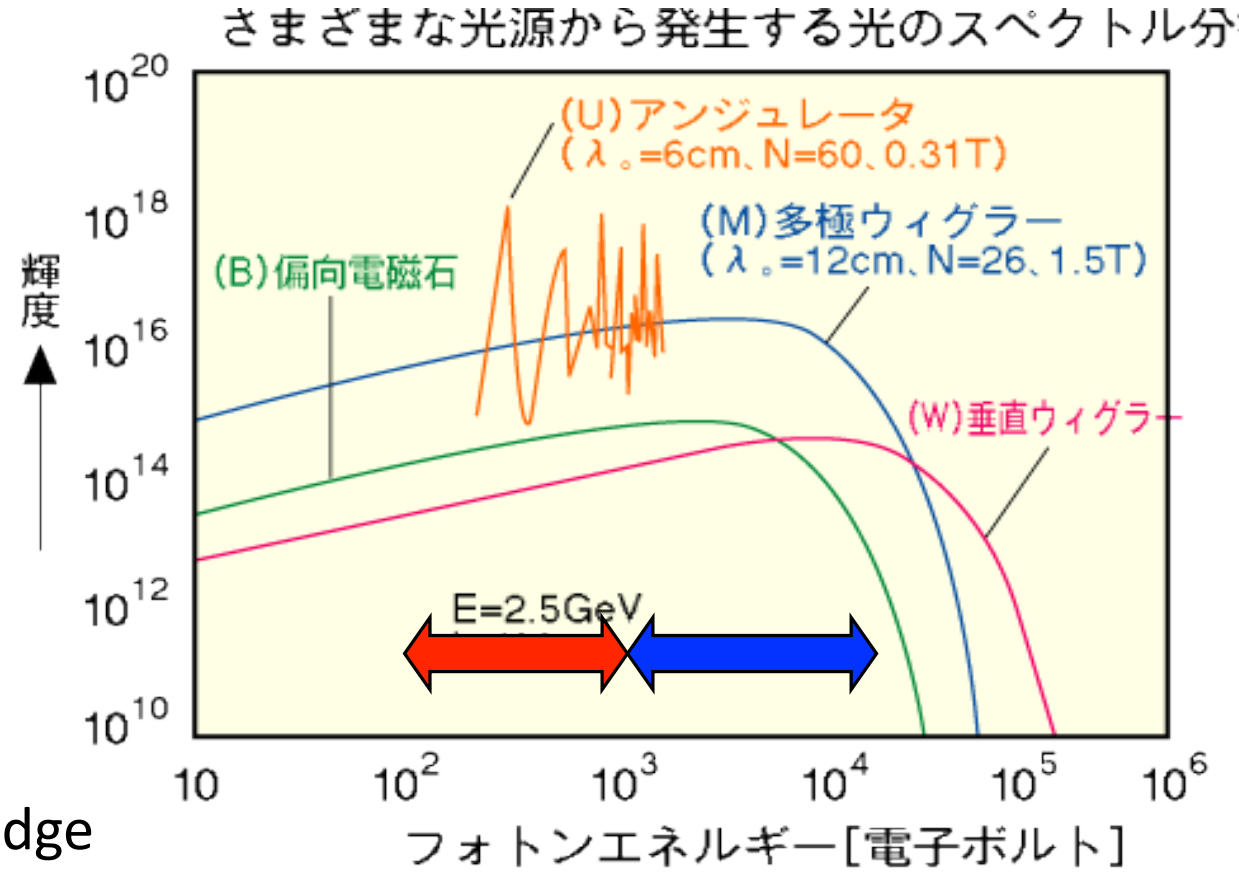


挿入光源（Insertion Device）
Undulator, Wiggler

pfwww.kek.jp


THE ELECTROMAGNETIC SPECTRUM
WAVELENGTH SIZE
Soccer Field
House
Baseball
This Period
Cell
Bacteria
Virus
Protein
Water Molecule
WAVELENGTH (in meters)
10^3 10^2 10^1 1 10^-1 10^-2 10^-3 10^-4 10^-5 10^-6 10^-7 10^-8 10^-9 10^-10 10^-11 10^-12
COMMON NAME
RADIO WAVES
INFRARED
ULTRAVIOLET
"HARD" X RAYS
VISIBLE
MICROWAVES
"SOFT" X RAYS
GAMMA RAYS
ACCELERATOR-BASED LIGHT SOURCES
TERAHERTZ
"HARD" X RAYS
COMMON SOURCES
AM Radio
FM Radio
Microwave Oven
Radar
People
Light Bulb
UV Lamp
X-Ray Machine
Radioactive Elements
FREQUENCY (waves per second)
10^6 10^7 10^8 10^9 10^10 10^11 10^12 10^13 10^14 10^15 10^16 10^17 10^18 10^19 10^20
ENERGY OF ONE PHOTON (electron volts)
10^-9 10^-8 10^-7 10^-6 10^-5 10^-4 10^-3 10^-2 10^-1 1 10^1 10^2 10^3 10^4 10^5 10^6

Light sources and spectra



C, N, O *K*-edge

250-600 eV

Fe, Co, Ni... *L*-edge

650-900 eV

軟X線 (Soft x-ray)

...Fe, Co, Ni,... *K*-edge

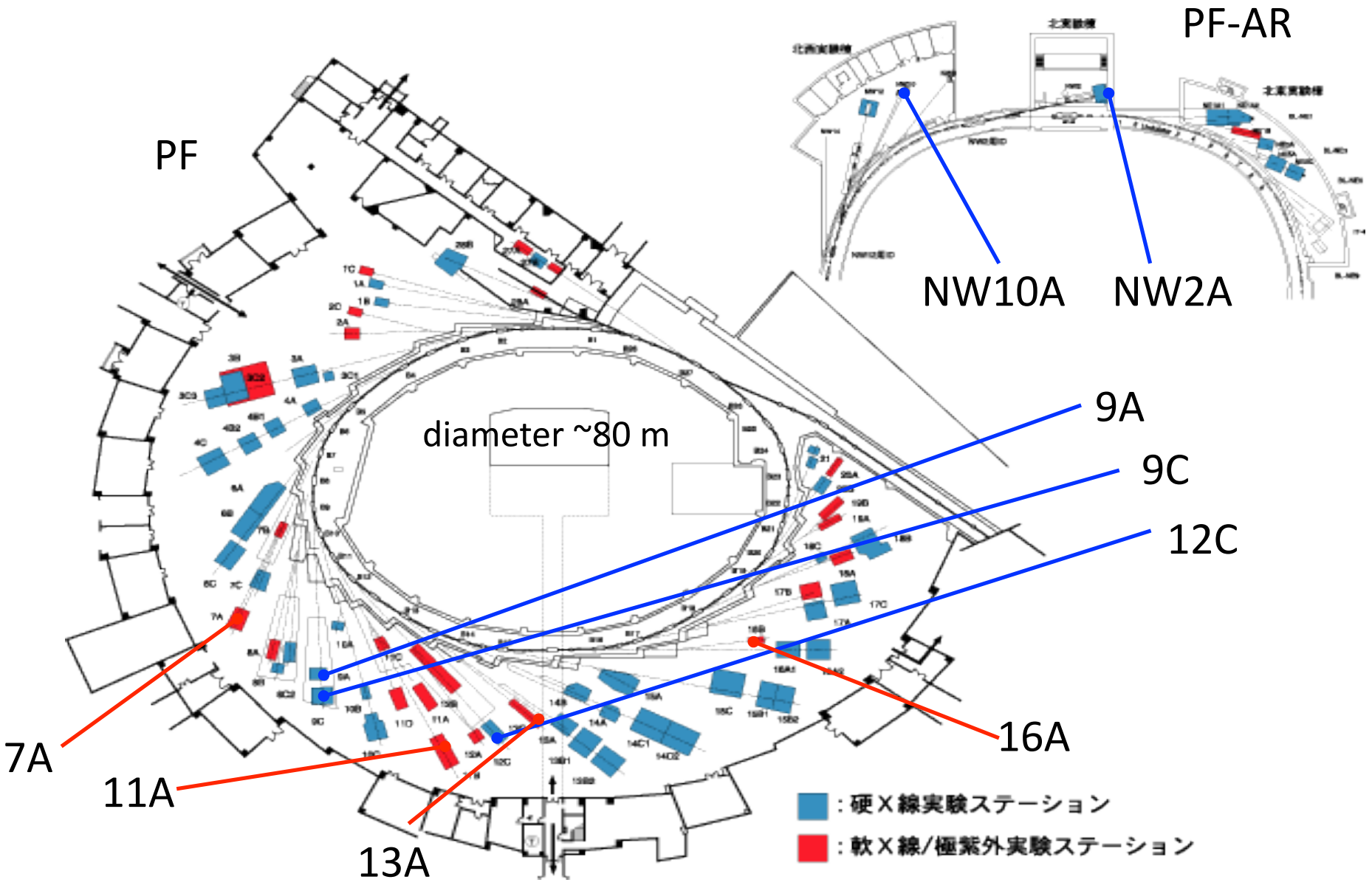
4-10 keV

硬X線 (Hard x-ray)

Pd *K*-edge

23 keV

Beamlines


PF
PF-AR
NW10A
NW2A
diameter ~80 m
9A
9C
12C
7A
11A
13A
16A
：硬Ｘ線実験ステーション
：軟Ｘ線/極紫外実験ステーション

XAFS

XAFS: X-ray Absorption Fine Structure, X線吸収微細構造

軟X線領域 : ~200 – 2000 eV ← *超高真空が必要*
(Soft x-ray) (~10^{-8} Pa)

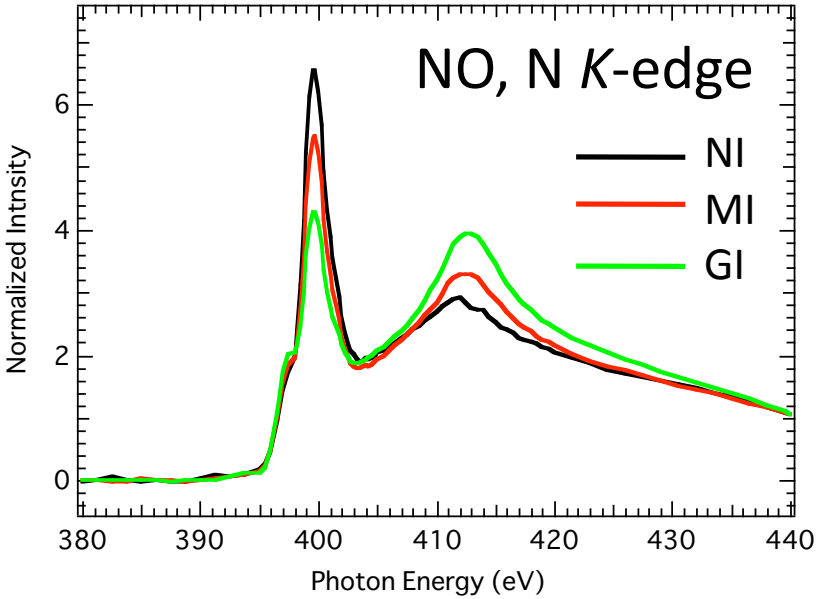
XAS (X-ray Absorption Spectroscopy) とも言う

硬X線領域 : ~2 keV – どこまでも
(Hard x-ray) ~42 keV (at PF-AR NW10A)
~60 keV, 113 keV (at SPring-8 BL01B1)

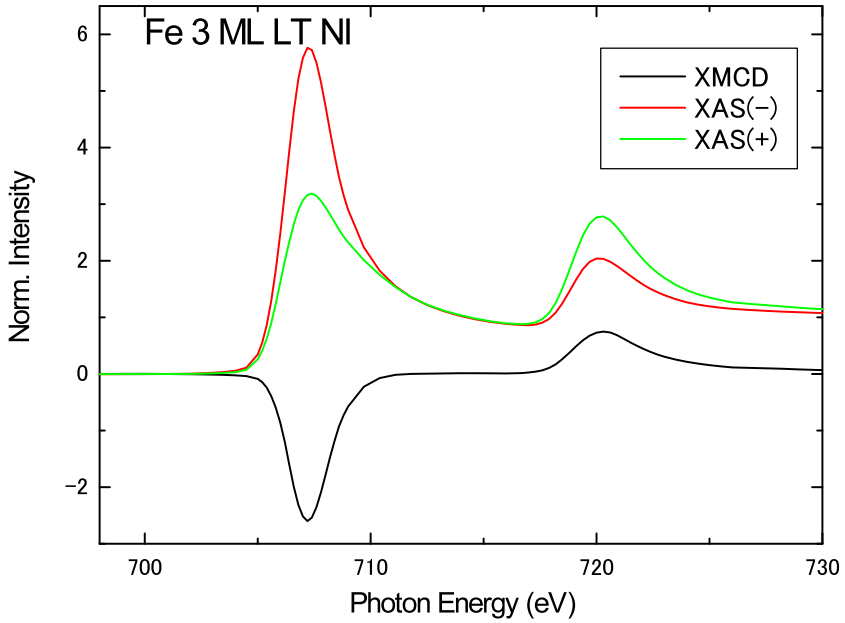
~2 keV – 4 keV: Hard x-rayの中では、”Soft”と呼ばれる

軟X線領域のX線吸収分光

NEXAFS: Near Edge X-ray Absorption Fine Structure



XMCD: X-ray Magnetic Circular Dichroism



NEXAFSから分かること

- 空準位のエネルギーと部分状態密度

  ⇒ LUMO, LUMO+1・・など空軌道の情報

- 空準位への遷移モーメントの方向

  ⇒ 吸着分子や固体の配向情報

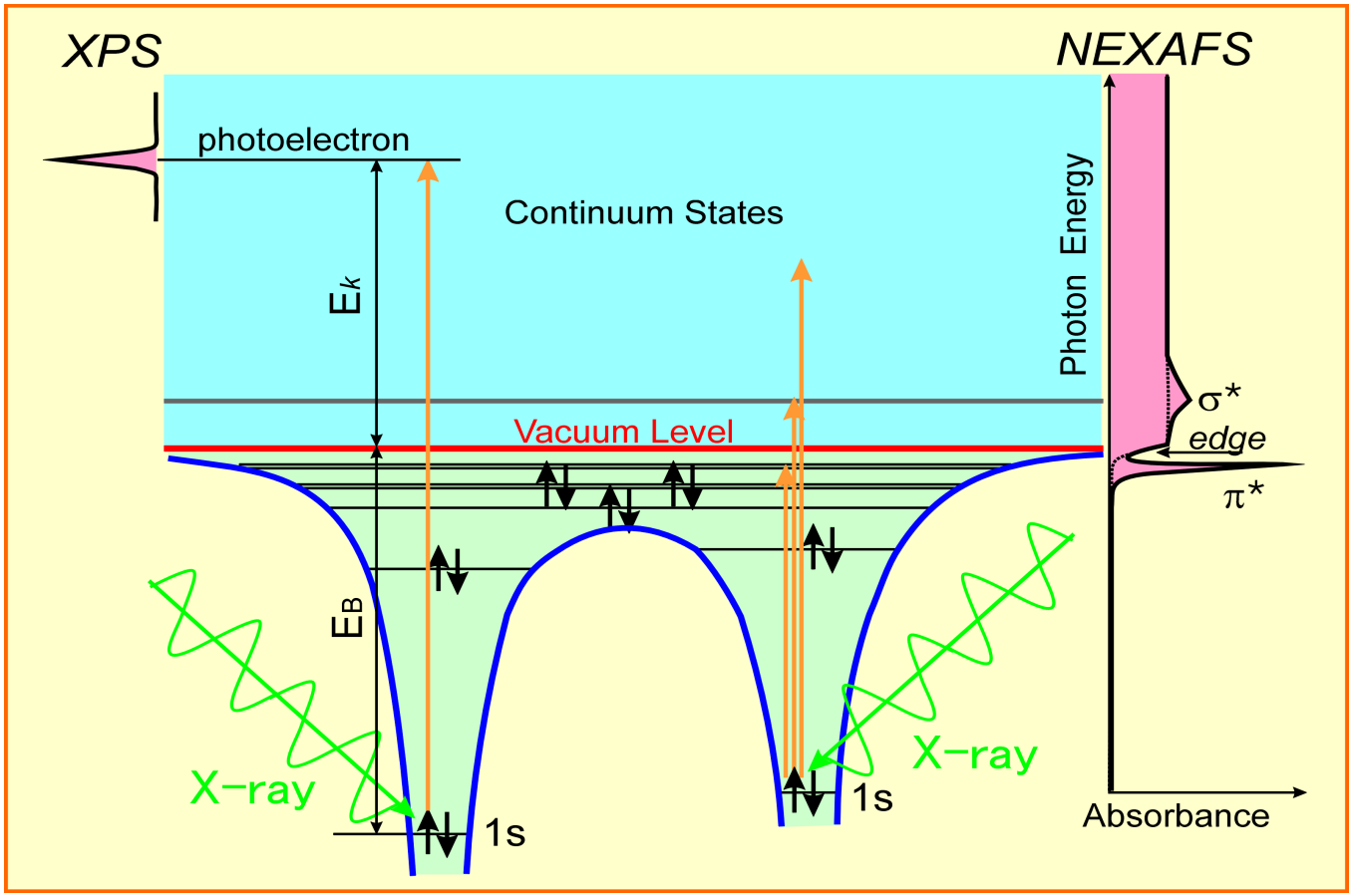
- ある空準位への遷移モーメントを持つものの量

  ⇒ 吸着分子の被覆率

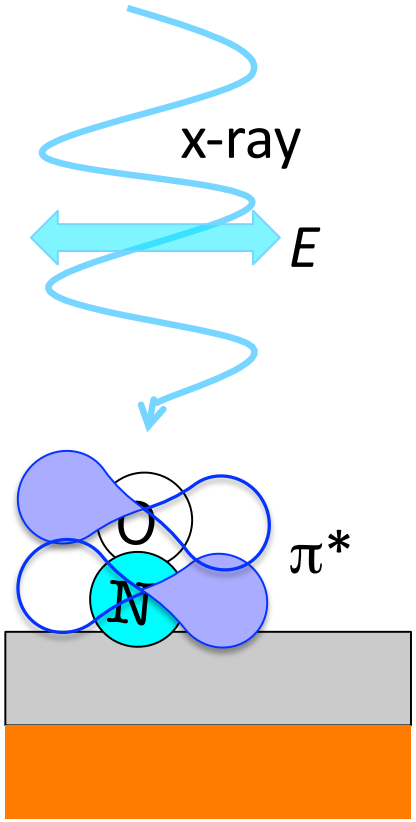
Near-Edge X-ray Absorption Fine Structure (NEXAFS)

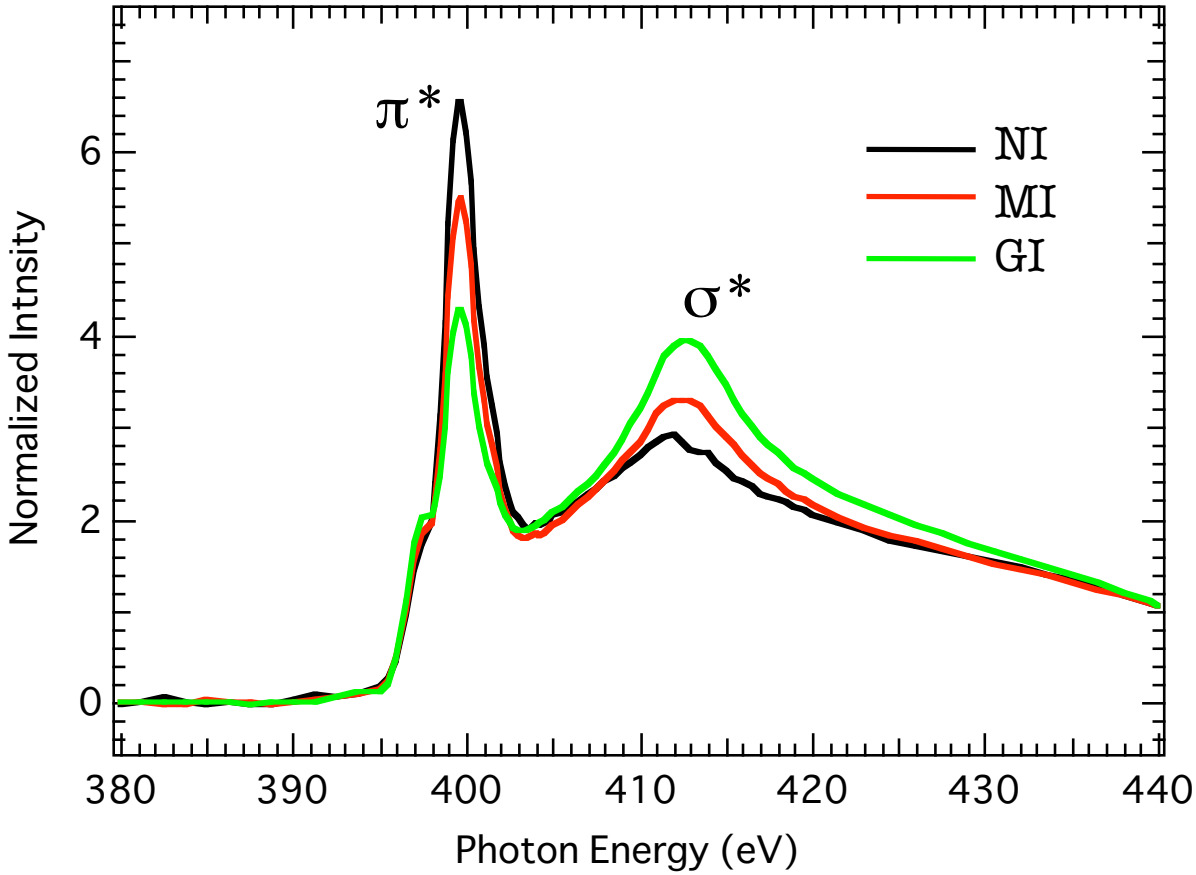
特徴

- 元素選択性
- （表面で）1 ML以下の分子を定量的に観測できる
- 局所的な分子の配向構造が見える (偏光依存性から)
- 局所電子構造が見える (unoccupied states)



N-*K* NEXAFS of NO: NO/Fe/Cu(001)





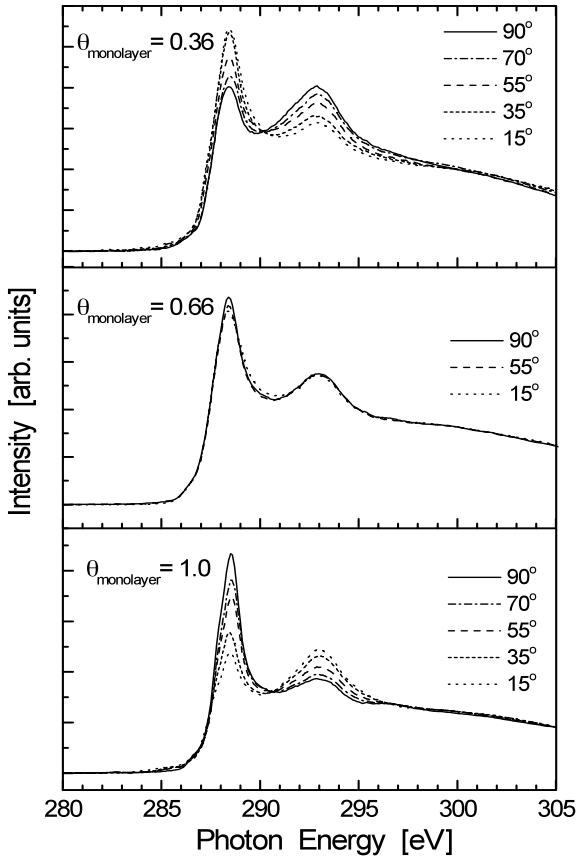
large π* peak for Normal incidence (NI)

NO molecules: nearly perpendicular to the plane

NEXAFSの応用例 （吸着分子の配向情報）

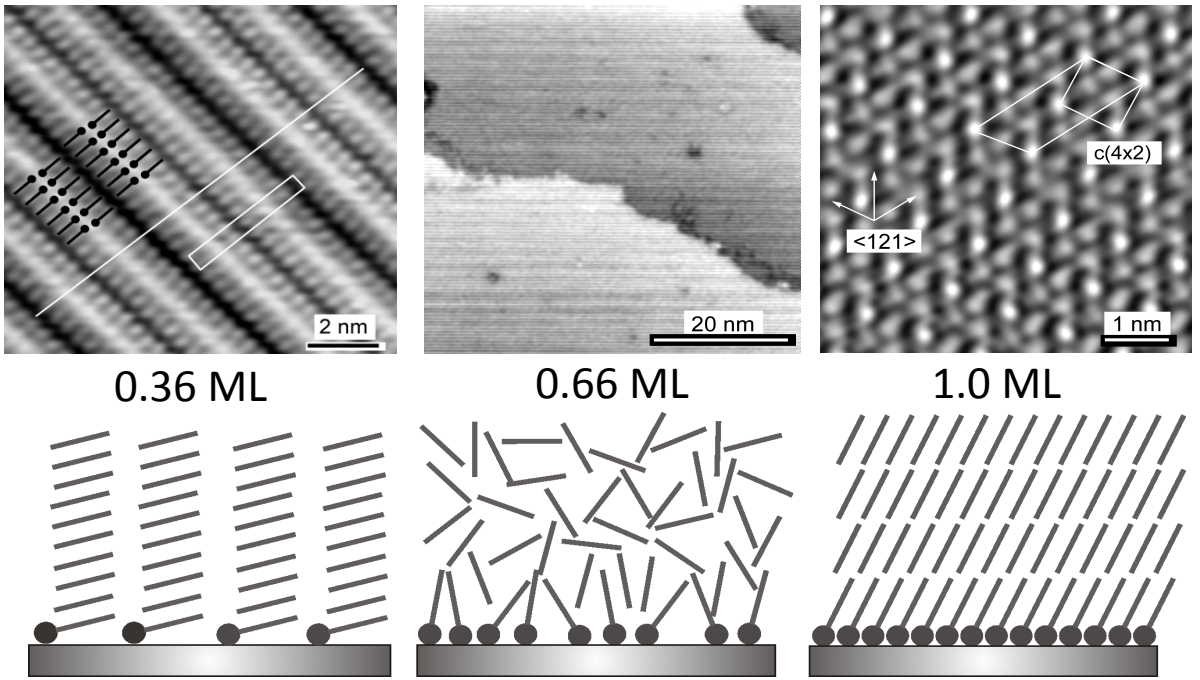
多層C_6H_{14}/単層$C_6H_{13}S$/Au(111)に対するC-K NEXAFSによって観測された

表面第1層をtemplateとする多層配向



表面第1層の分子密度（配向）を変えたときの
C_6H_{14}/$C_6H_{13}S$/Au(111)に対するC-K NEXAFS

表面第1層のチオレート単分子膜のSTM像



配向モデル

H. Kondoh et al. *Langmuir* **17**, 8178 (2001).

XMCDで分かること

元素選択的に

- 磁化の向き
- スピンと軌道の磁気モーメント

What is XMCD?

- Normal one photon absorption (NEXAFS)
- Absorption spectroscopy with circularly polarized light
- Take the difference of the "+" and "-" XAS

$$\vec{r} = x\vec{e}_x + y\vec{e}_y + z\vec{e}_z$$

$$\vec{e} = \mp\frac{1}{\sqrt{2}}\left(\vec{e}_x \pm i\vec{e}_y\right)$$

$$P_1^{(1)} = \vec{e}\cdot\vec{r} = -\frac{1}{\sqrt{2}}(x+iy) = r\sqrt{\frac{4\pi}{3}}Y_1^1 \quad : Right$$

$$P_{-1}^{(1)} = \vec{e}\cdot\vec{r} = \frac{1}{\sqrt{2}}(x-iy) = r\sqrt{\frac{4\pi}{3}}Y_1^{-1} \quad : Left$$

selection rules:

orbital angular momentum quantum number: $\Delta l = \pm 1$

magnetic quantum number: $\Delta m_l = +1$ (Right), -1 (Left)

XMCD signal intensity

$$\Delta I = I(+) - I(-)$$

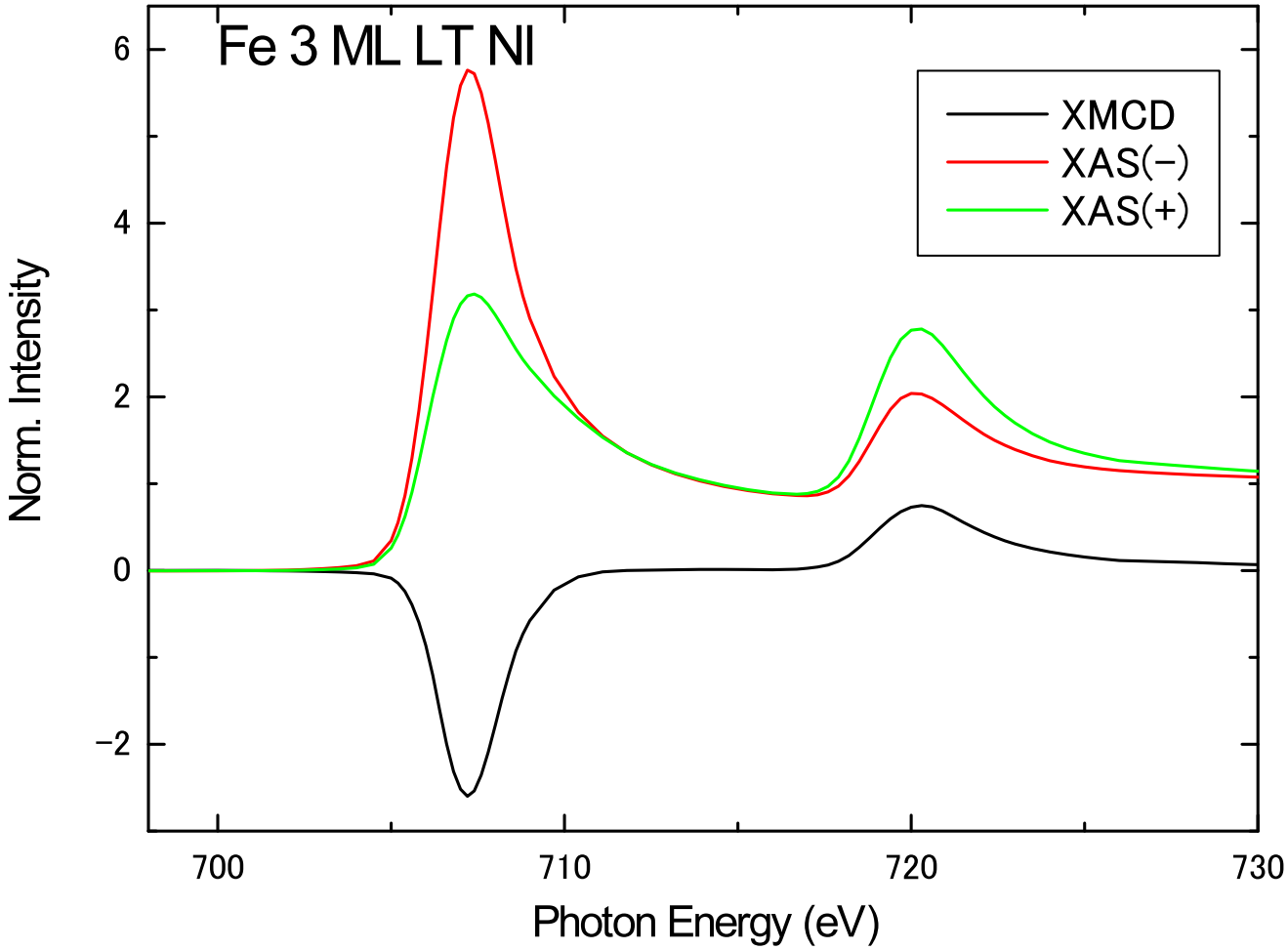
$I(+)$: XAS with photon spin parallel to majority spin

$I(-)$: XAS with photon spin antiparallel to majority spin

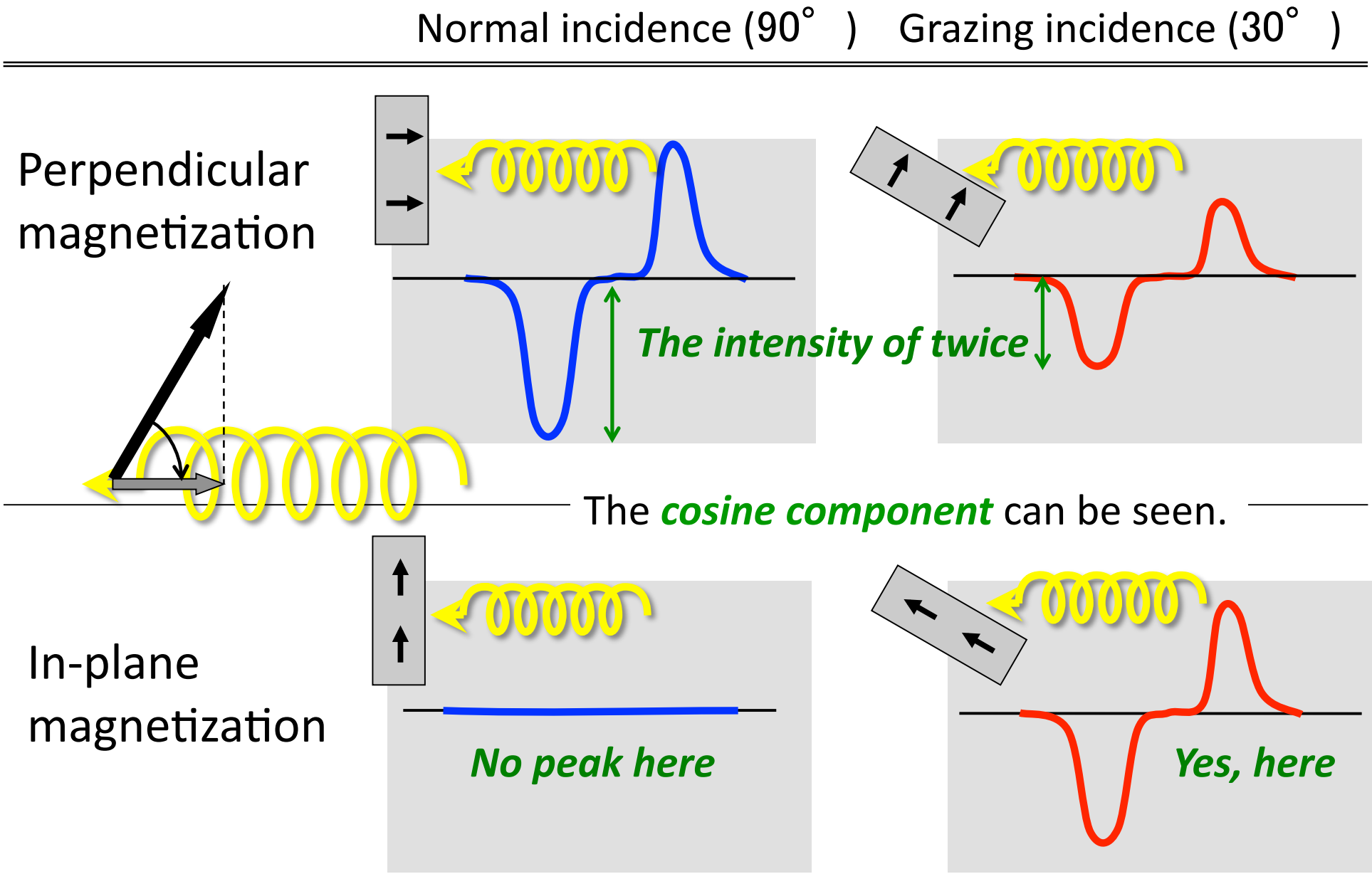
XAS(+) - XAS(-) = XMCD

X-ray Absorption Spectrum

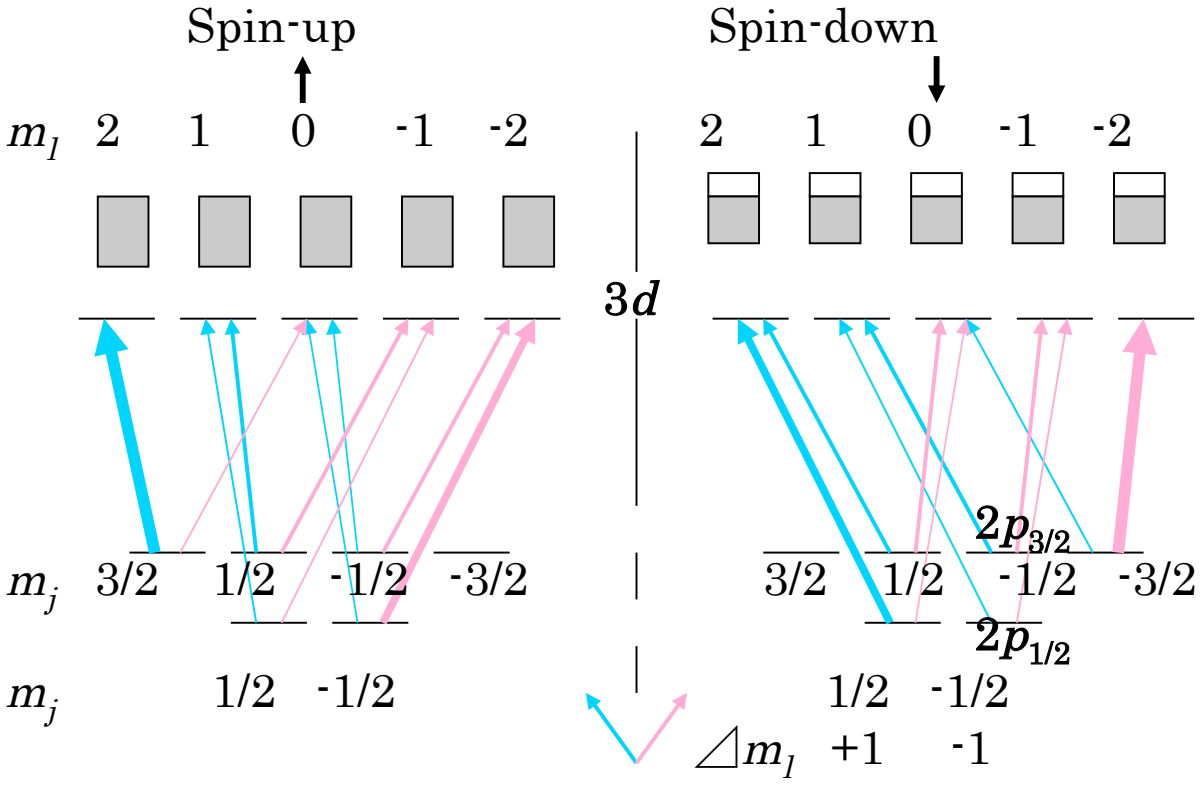
X-ray Magnetic Circular Dichroism

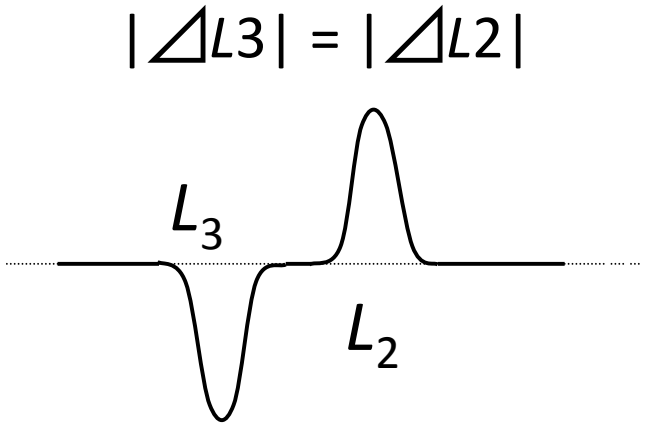


XMCD spectra and magnetization direction



XMCD: *d* orbitals without s-o interaction





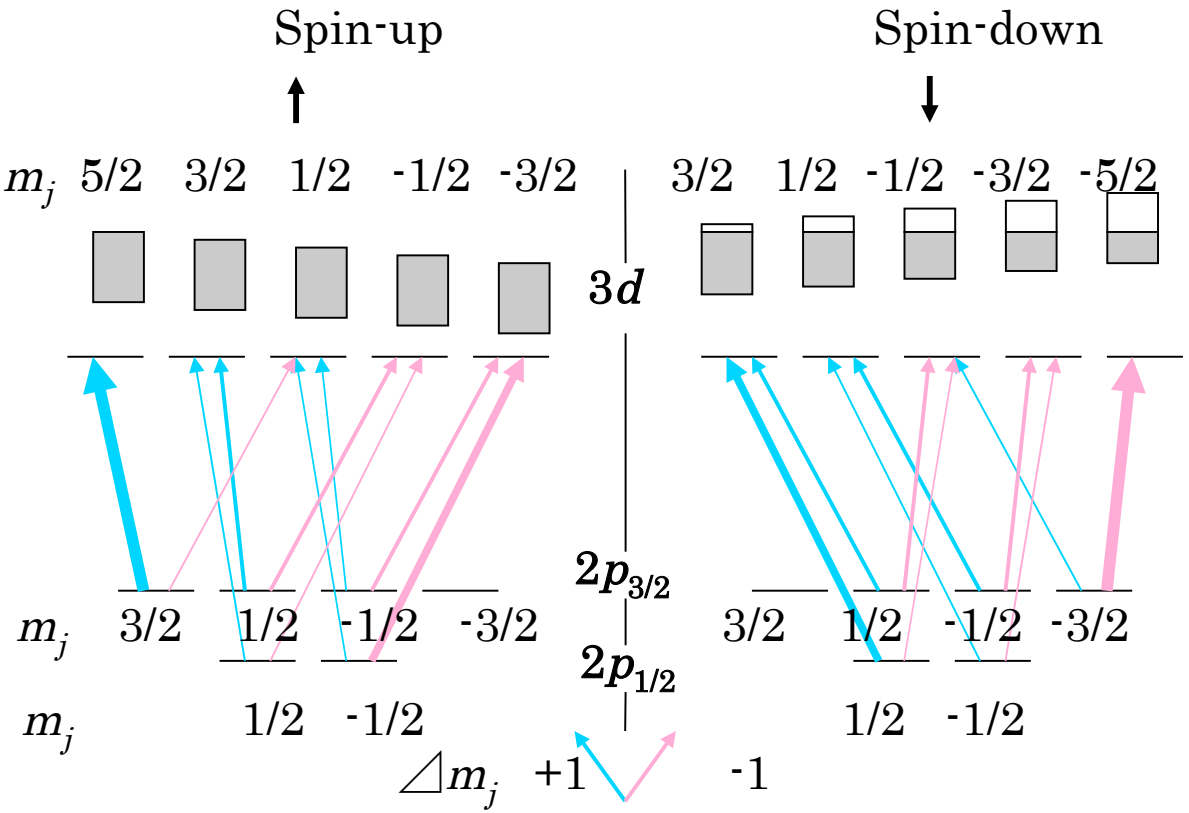
d orbitals without spin-orbit interaction

Quenched orbital magnetic moment ⇨

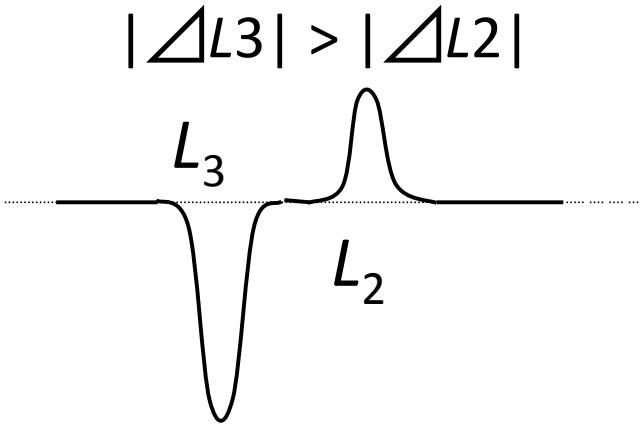
Symmetric shape of XMCD

The same XMCD intensities both at L_3 edge and L_2 edge

XMCD: *d* orbitals with s-o interaction

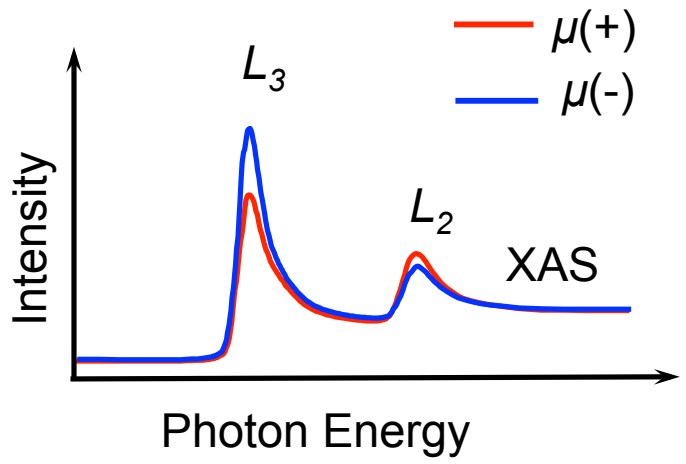


d orbitals with spin-orbit interaction

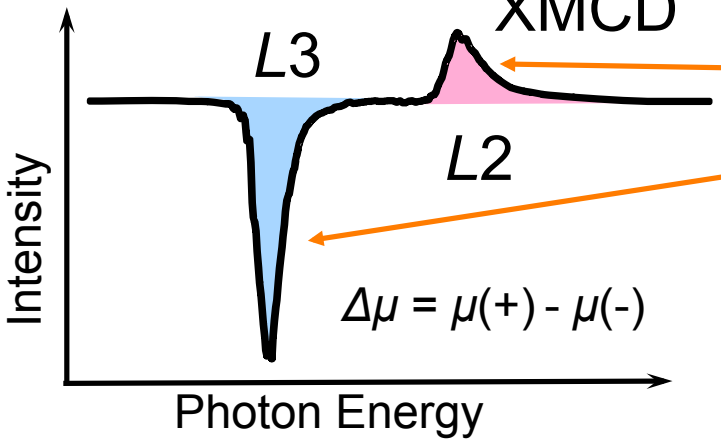


Survived orbital magnetic moment ⇨ Asymmetric shape of XMCD

Sum rules: XMCD spectra and magnetic moments



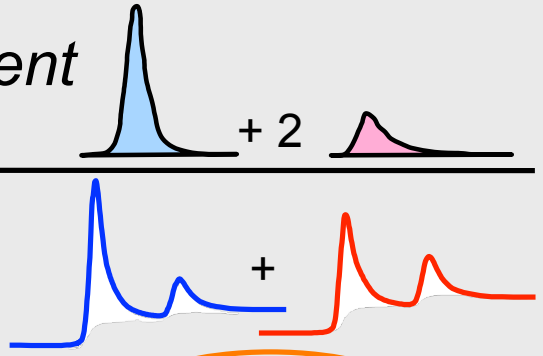
difference



Sum Rules $*N_h$; hole number

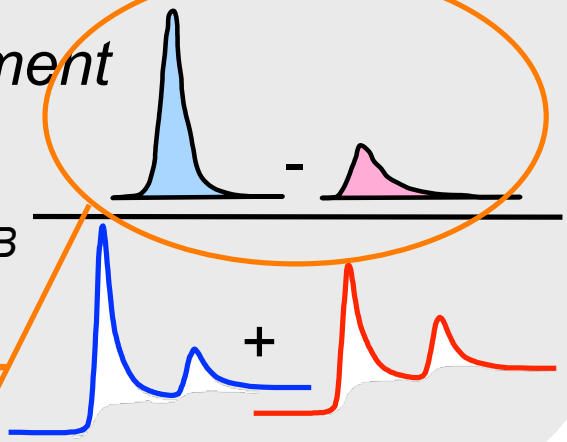
Spin magnetic moment

$m_s = 2N_h\mu_B$



Orbital magnetic moment

$m_l = 4/3N_h\,\mu_B$



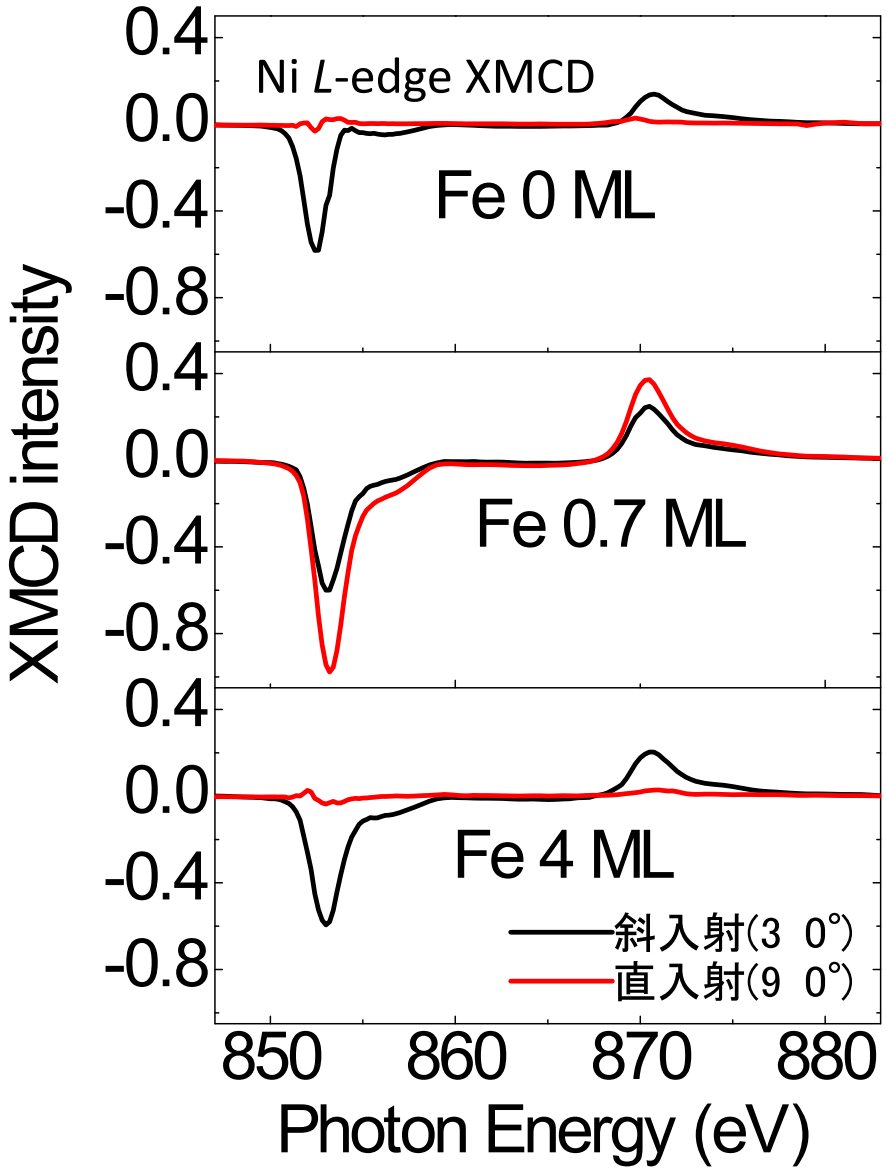
difference between $L_3$and L_2

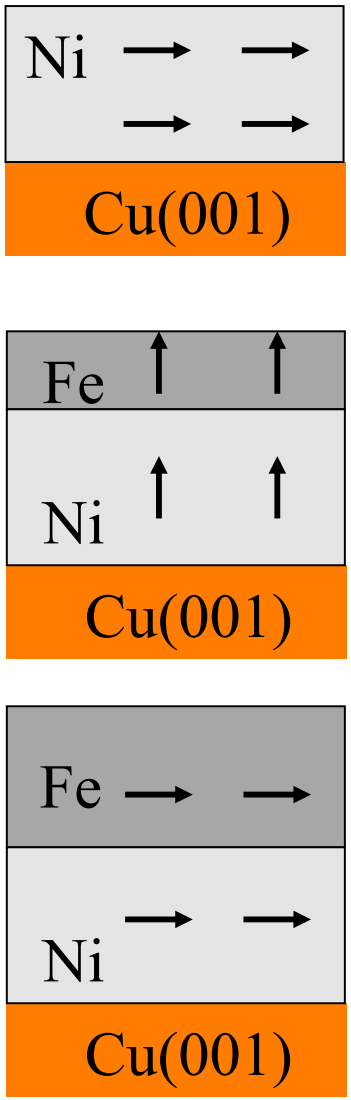
↕

Orbital magnetic moment

B. T. Thole, *et al.*, Phys. Rev. Lett. **68**, 1943 (1992)
P. Carra, *et al.*, Phys. Rev. Lett. **70**, 694 (1993)

Ni/Cu(001)にFeを蒸着していくと…





Ni(7.5 ML)/Cu(001)

Fe なし

面内磁化

Fe 0.7 ML

面直磁化

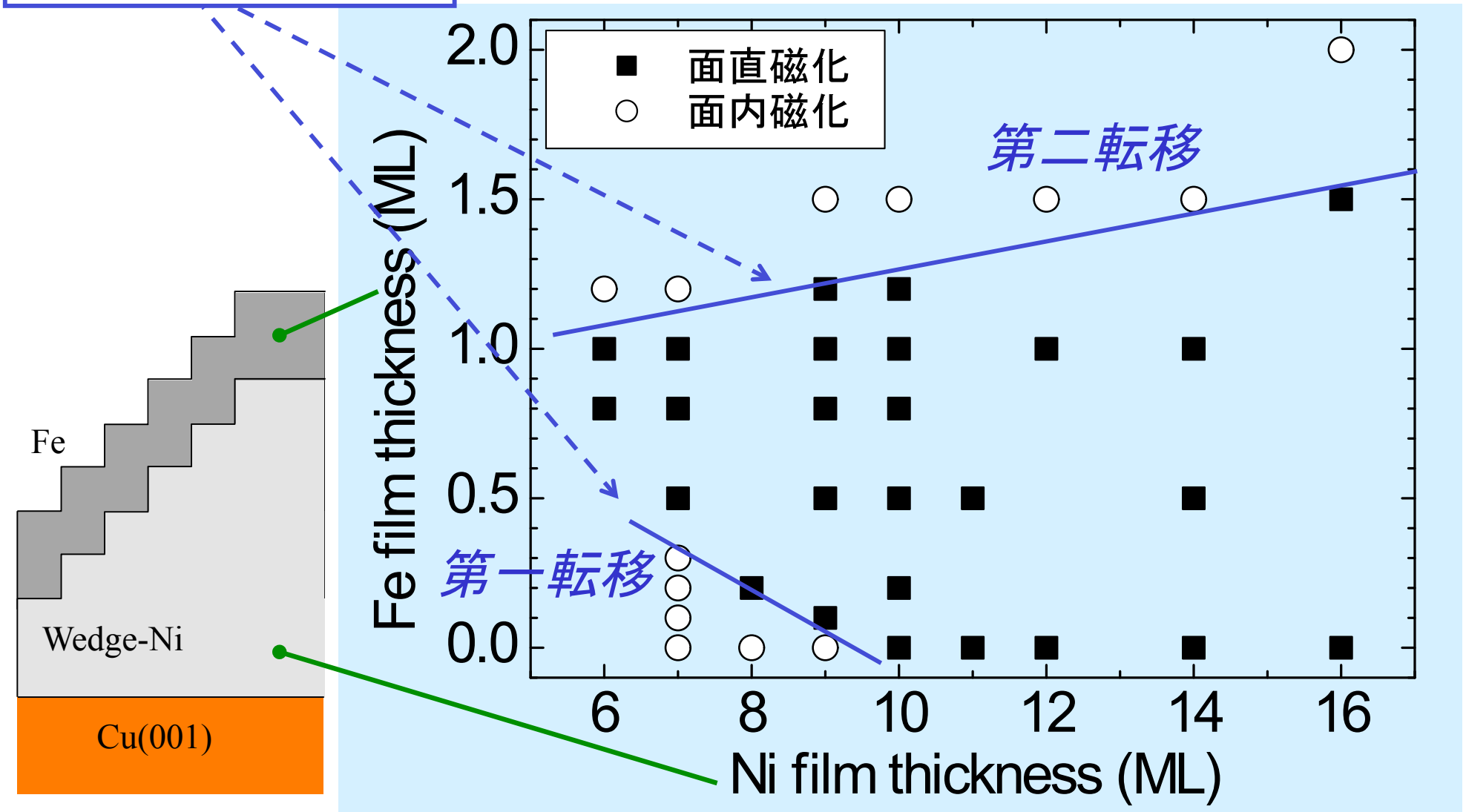
Fe 4 ML

面内磁化

2回の
スピン再配列転移

Fe/Ni/Cu(001)の磁気異方性相図

スピン再配列転移



NEXAFS, XMCDでわかること

We can get from...

元素選択的に

NEXAFS:

- どんな分子が（表面近傍に）存在するか
- その分子がどんな方向を向いているか
- その分子がどのくらいあるか

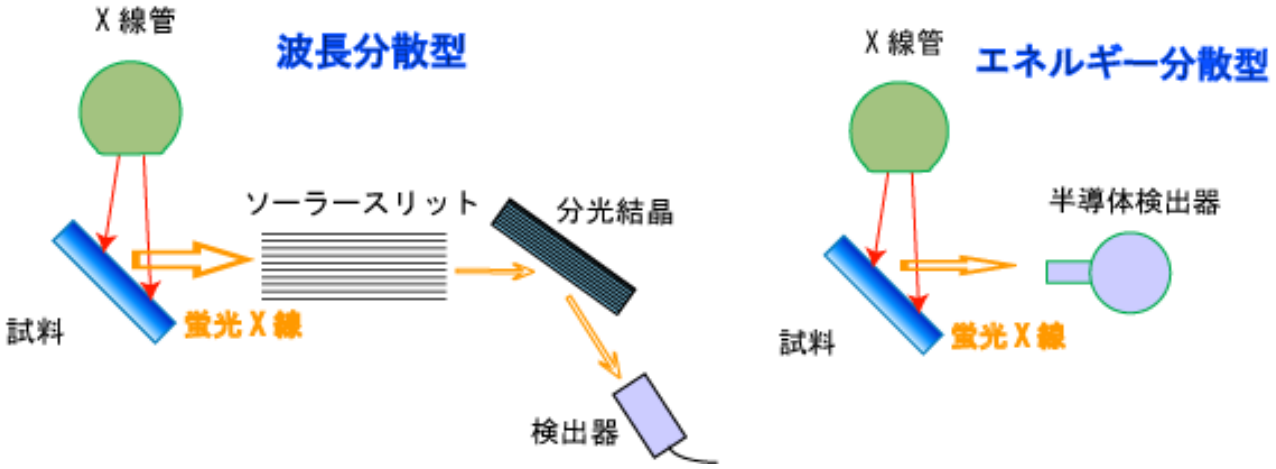
XMCD:

- 磁化の方向
- スピンと軌道の磁気モーメント

蛍光X線分析

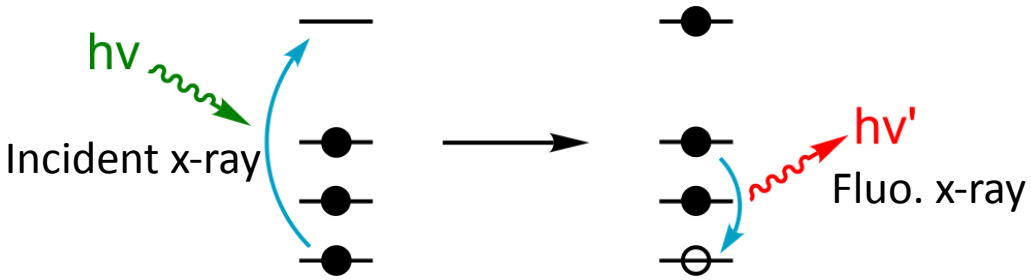
(X-ray Fluorescence Analysis, XRF)

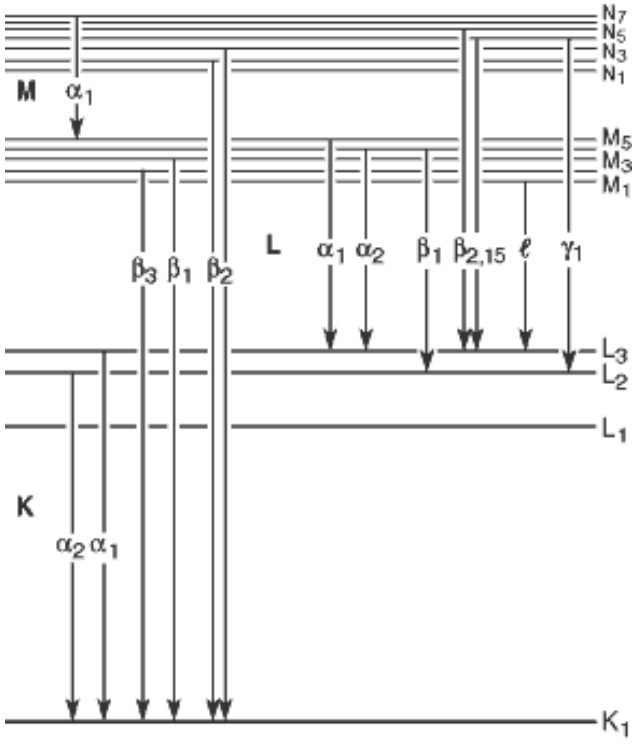
(1) 試料の化学的処理は不要（非破壊分析）。
(2) 適用元素はNaからUまでの全元素で、測定時間も短い。多元素分析も可能。
(3) 分析可能範囲が、1ppm程度から100%までと広い。しかも分析精度が高い。



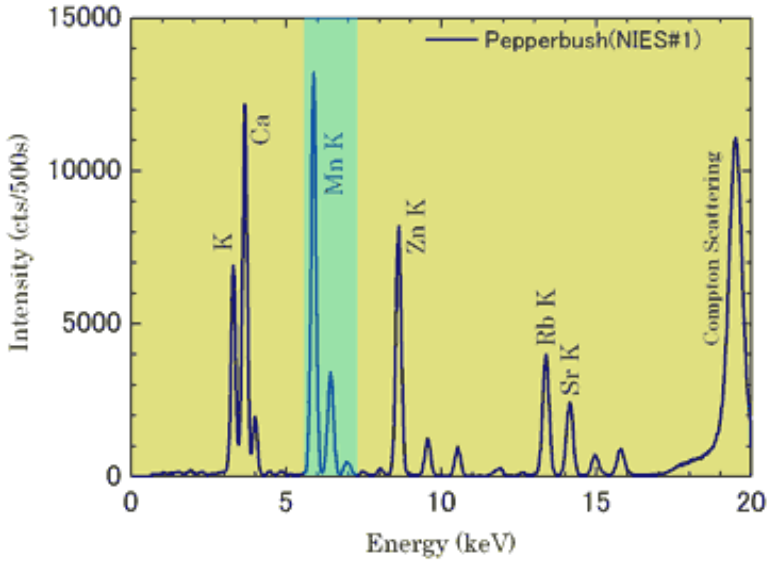
http://pfwww.kek.jp/iida/xrf.htm

Element specific emission: Fluorescent x-ray





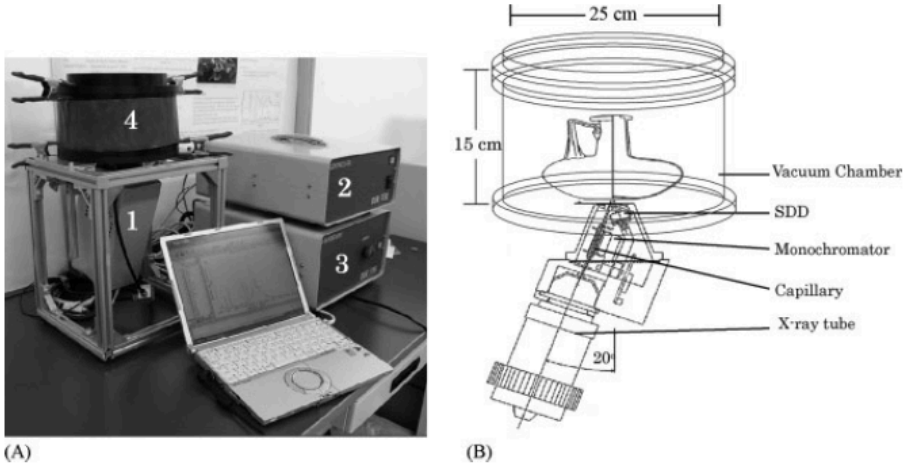
Element	Kα1	Kα2
22 Ti	4,510.84	4,504.86
23 V	4,952.20	4,944.64
24 Cr	5,414.72	5,405.509
25 Mn	5,898.75	5,887.65
26 Fe	6,403.84	6,390.84
27 Co	6,930.32	6,915.30
28 Ni	7,478.15	7,460.89
29 Cu	8,047.78	8,027.83
30 Zn	8,638.86	8,615.78

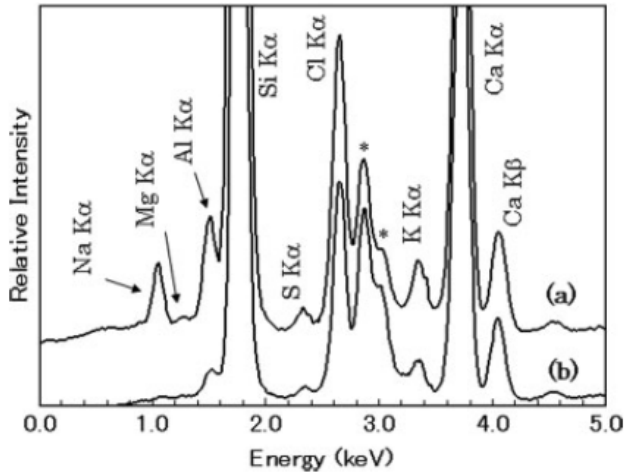


XRFを使った研究例: 古代のガラス

Archaeological analysis of Roman glass excavated from Zadar, Croatia, by a newly developed portable XRF spectrometer for glass

K. Tantrakarn,[a] N. Kato,[a] A. Hokura,[a] I. Nakai,[a]* Y. Fujii[b] and S. Gluščević[c]





各元素の含有量がわかる

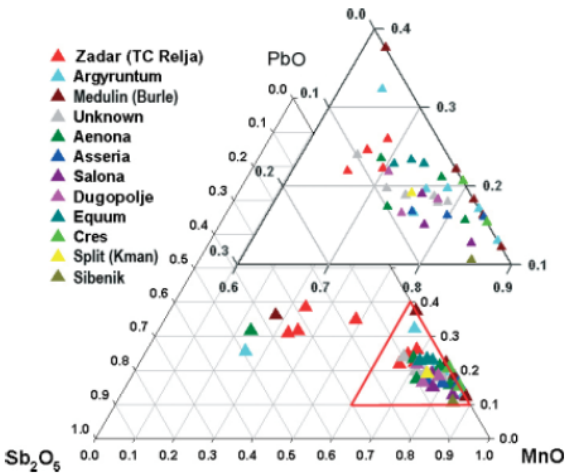
Na_2O, MgO, Al_2O_3, PdO, CuO, ...

X-ray Spectrometry **38**, 121 (2009)

数十%からppmという幅広い濃度で分析できる

Table 3. Glass types and their average chemical compositions

	Bell-shaped flask		Depression flask		Square jug		Cinerary urn		Glass ingot
	Mn decolorizers N = 40	Sb decolorizers N = 8	Mn decolorizers N = 15	Sb decolorizers N = 4	Mn decolorizers N = 4	Sb decolorizers N = 3	Mn decolorizers N = 5	Sb decolorizers N = 1	N = 1
Na_2O (wt%)	14.6 ± 4.5	11.5 ± 6.3	16.4 ± 0.6	24.9 ± 5.5	20.0 ± 3.2	19.6 ± 3.9	18.7 ± 5.8	9.2	14.8
MgO (wt%)	0.60 ± 0.06	0.65 ± 0.05	0.59 ± 0.02	0.66 ± 0.02	0.49 ± 0.24	0.09 ± 0.03	0.16 ± 0.24	0.02	0.06
Al_2O_3 (wt%)	1.28 ± 0.19	1.21 ± 0.33	1.98 ± 0.69	1.73 ± 0.17	1.26 ± 0.17	1.10 ± 0.05	1.10 ± 0.13	1.30	1.11
K_2O (wt%)	0.19 ± 0.06	0.20 ± 0.06	0.23 ± 0.11	0.27 ± 0.02	0.26 ± 0.08	0.26 ± 0.04	0.19 ± 0.06	0.22	0.15
CaO (wt%)	4.25 ± 0.50	3.58 ± 0.53	3.96 ± 0.33	4.64 ± 0.04	4.16 ± 0.44	3.68 ± 0.22	3.85 ± 0.54	3.22	3.32
MnO (wt%)	1.10 ± 0.15	1.05 ± 0.18	1.00 ± 0.12	1.05 ± 0.10	0.70 ± 0.09	0.80 ± 0.05	0.15 ± 0.01	0.15	0.82
Fe_2O_3 (wt%)	0.29 ± 0.05	0.32 ± 0.05	0.30 ± 0.05	0.39 ± 0.01	0.32 ± 0.08	0.34 ± 0.01	0.27 ± 0.06	0.30	0.24
PbO (ppm)	100 ± 30	360 ± 100	190 ± 70	470 ± 30	200 ± 190	1620 ± 360	250 ± 230	1000	90
SrO (ppm)	680 ± 90	580 ± 80	690 ± 20	700 ± 30	635 ± 85	560 ± 40	580 ± 50	530	550
CuO (ppm)	1100 ± 240	1220 ± 300	1410 ± 120	1640 ± 40	1480 ± 800	2070 ± 400	1640 ± 1320	1740	1020
Zr (ppm)	3580 ± 220	3520 ± 370	3800 ± 60	3840 ± 160	3630 ± 280	3560 ± 70	3550 ± 100	3700	3510
Sb_2O_3 (ppm)	1650 ± 1270	26300 ± 9800	2560 ± 1790	22500 ± 6300	2200 ± 1090	23500 ± 1900	2790 ± 2240	22000	1390

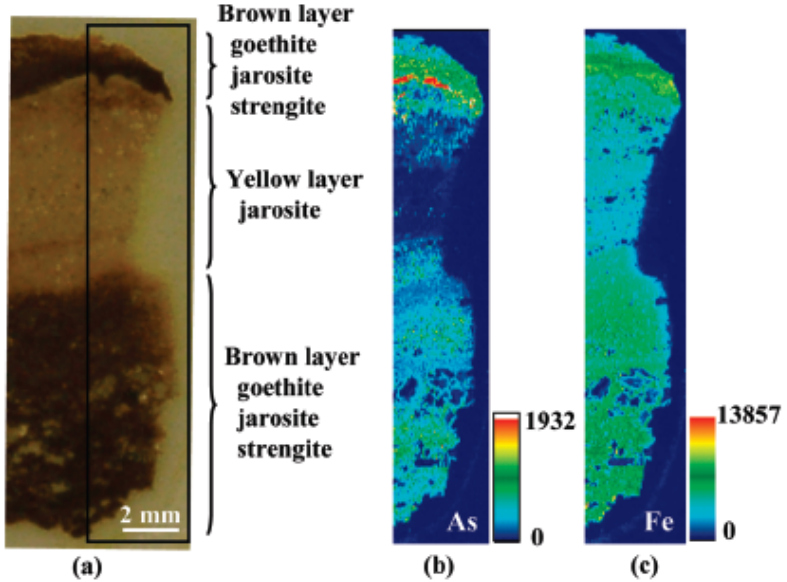


μ-XRFを使って元素マッピングの例

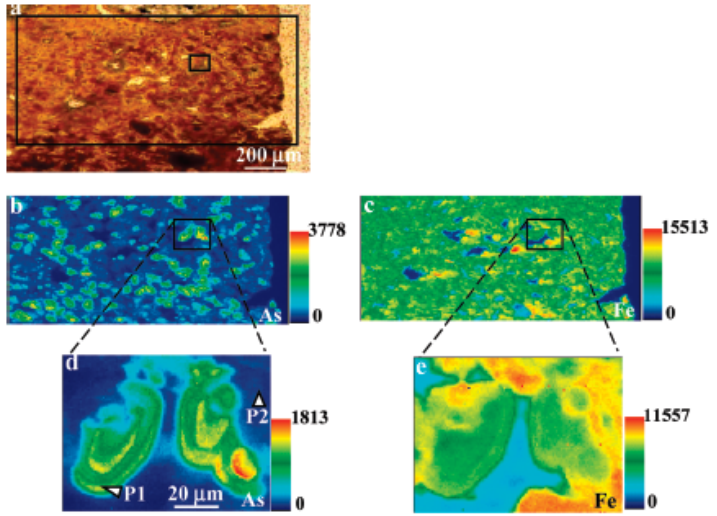
Chemical Speciation of Arsenic-Accumulating Mineral in a Sedimentary Iron Deposit by Synchrotron Radiation Multiple X-ray Analytical Techniques

SATOSHI ENDO,† YASUKO TERADA,‡
YASUHIRO KATO,§ AND IZUMI NAKAI*,†

鉱物中の元素の濃度分布が見える



As Fe



As Fe

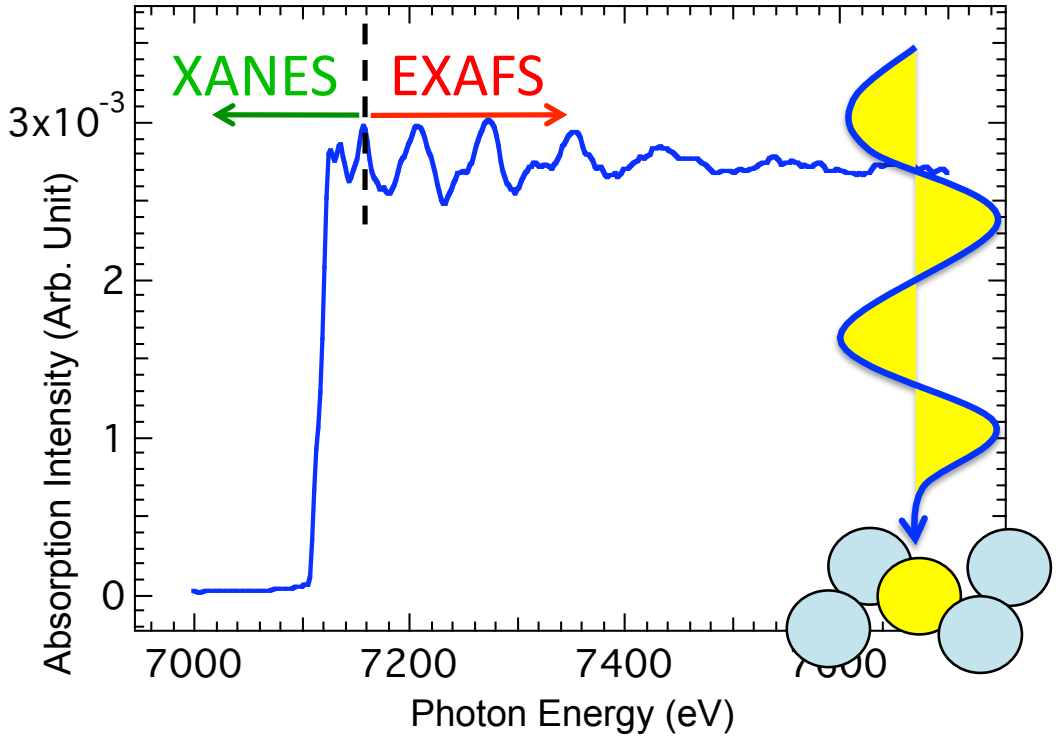
Environ. Sci. Technol. **42**, 7152 (2008)

XAFSって？ -XAFSデータが含むもの-

X-ray Absorption Fine Structure
（X線吸収微細構造）

電子状態
（価数）
対称性

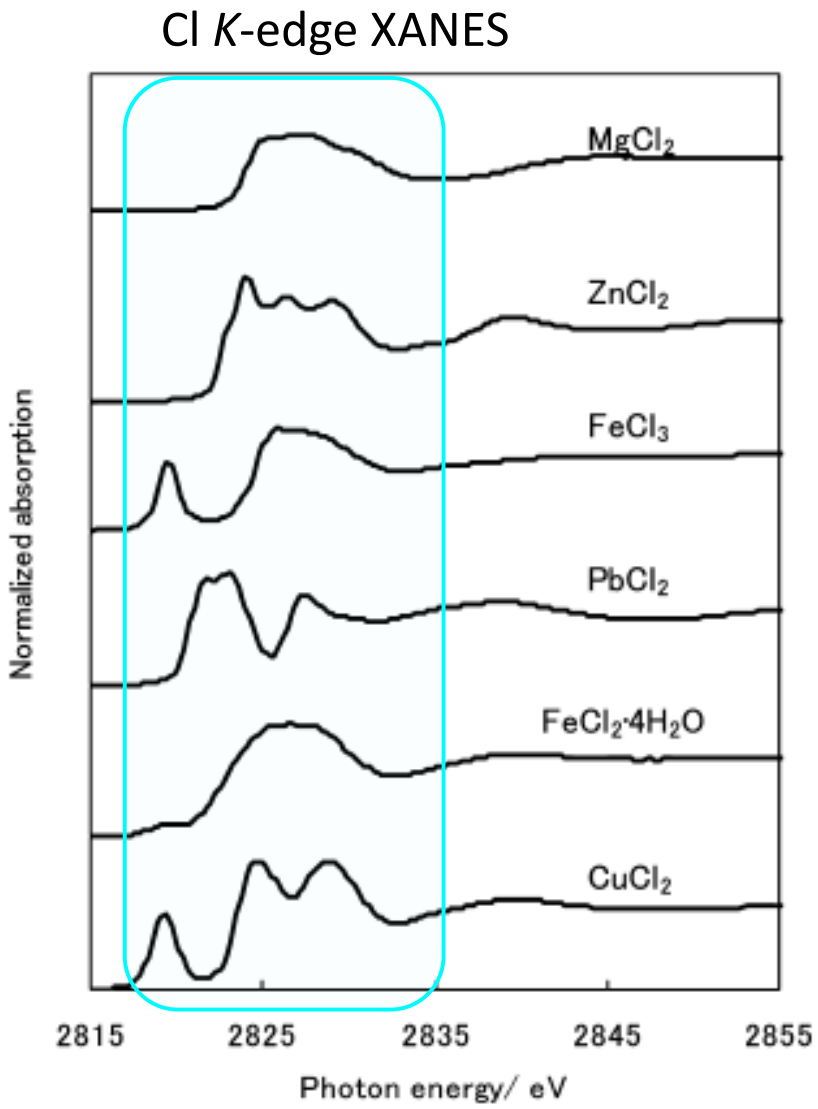
吸収原子と周辺の散乱原子との結合距離
周辺原子の数（配位数）、種類
周辺原子の分布の様子、熱振動



元素選択的に情報が得られる
局所構造を観測する
結晶のような周期性がなくてもOK
固相、液相、気相、何でも測定できる

XANES: X-ray Absorption Near Edge Structure
EXAFS: Extended X-ray Absorption Fine Structure

XANES tells us what your sample is.



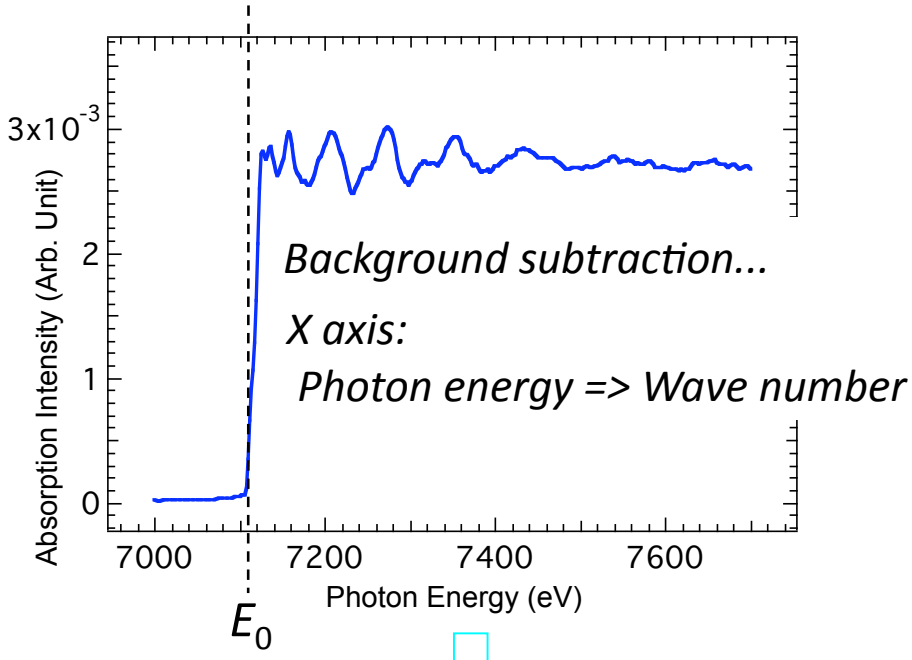
All these are metal chlorides.

But you can see some specific features in each spectrum.

So you would recognize what your sample is.

F. Zhu, *et al.,* Environ. Sci. Technol. **42**, 3932 (2008)

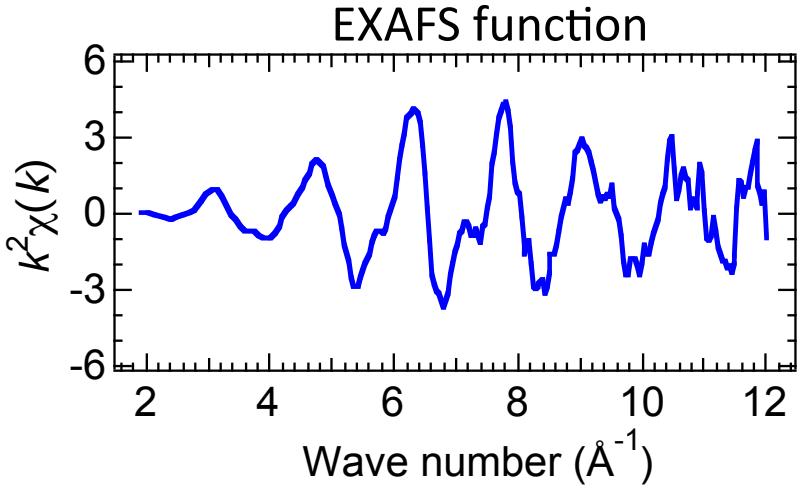
How to Obtain Bond Length by EXAFS



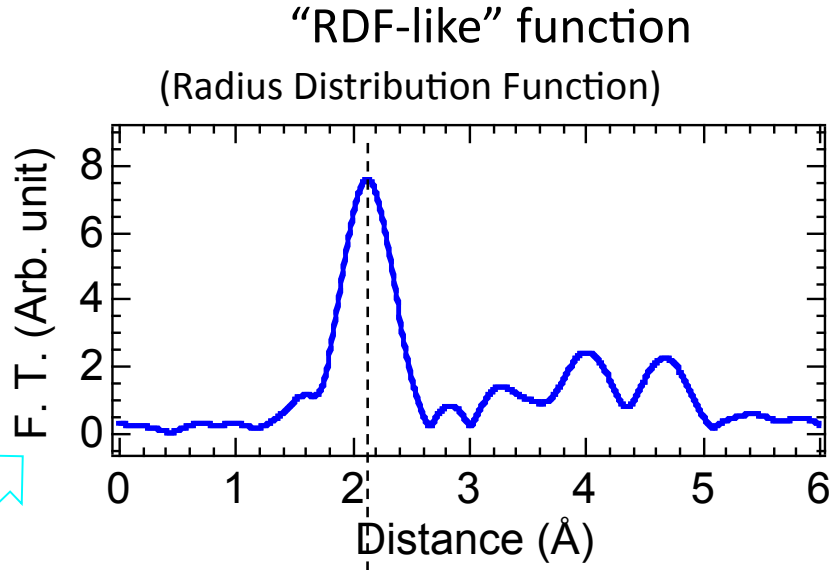
Background subtraction...

X axis:

Photon energy => Wave number



Fourier Transform



Nearest neighbor atomic distance

+ phase shift

Bond length

Peak area

Coordination number

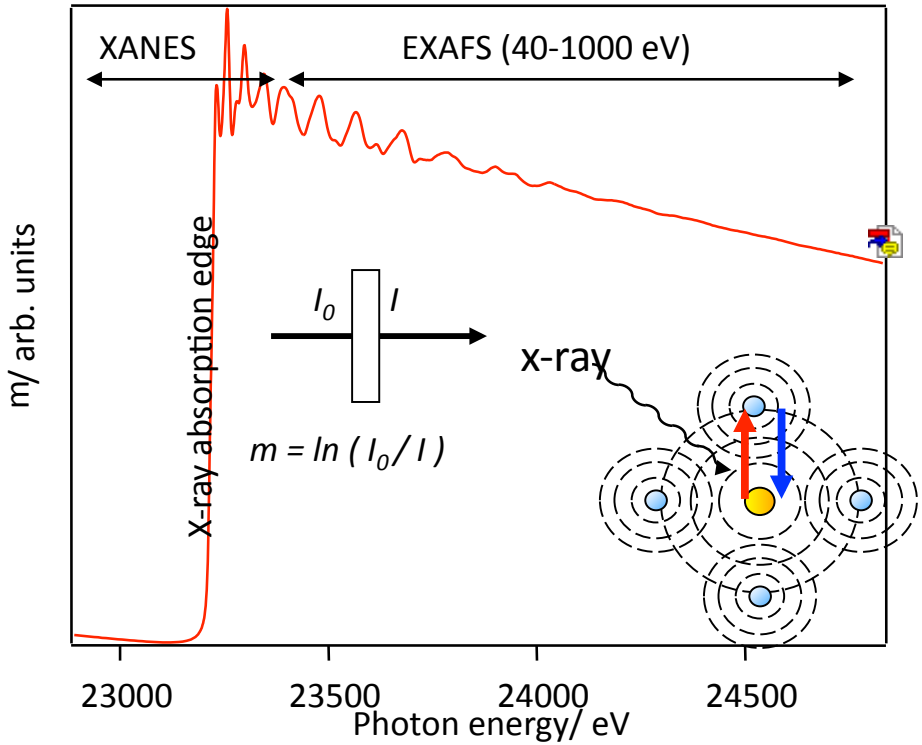
Simple things XAFS spectra give us

- XANES gives us... with element specificity
  - Valence state
    - We can determine our sample as a certain molecule or material.
  - Symmetry

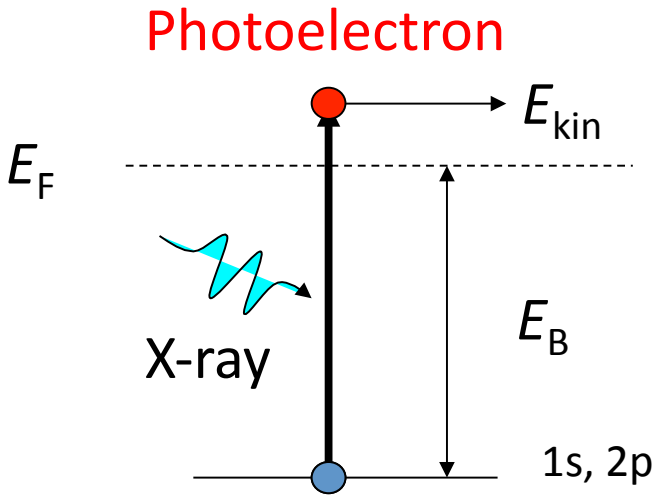
- EXAFS gives us...
  - Bond length
    - **A local structure** is given.
    - **Crystallinity, or long range order is not required**.
  - Coordination number (CN)
    - Simply, the number of atoms around the atom.
    - CN enables us to estimate sizes of nano clusters.

XAFS

- ✓ X-ray Absorption Fine Structure(XAFS)
  - ✓XANES(X-ray Absorption Near Edge Structure）
  - ✓EXAFS(Extended X-ray Absorption Fine Structure）



X-ray absorption spectrum

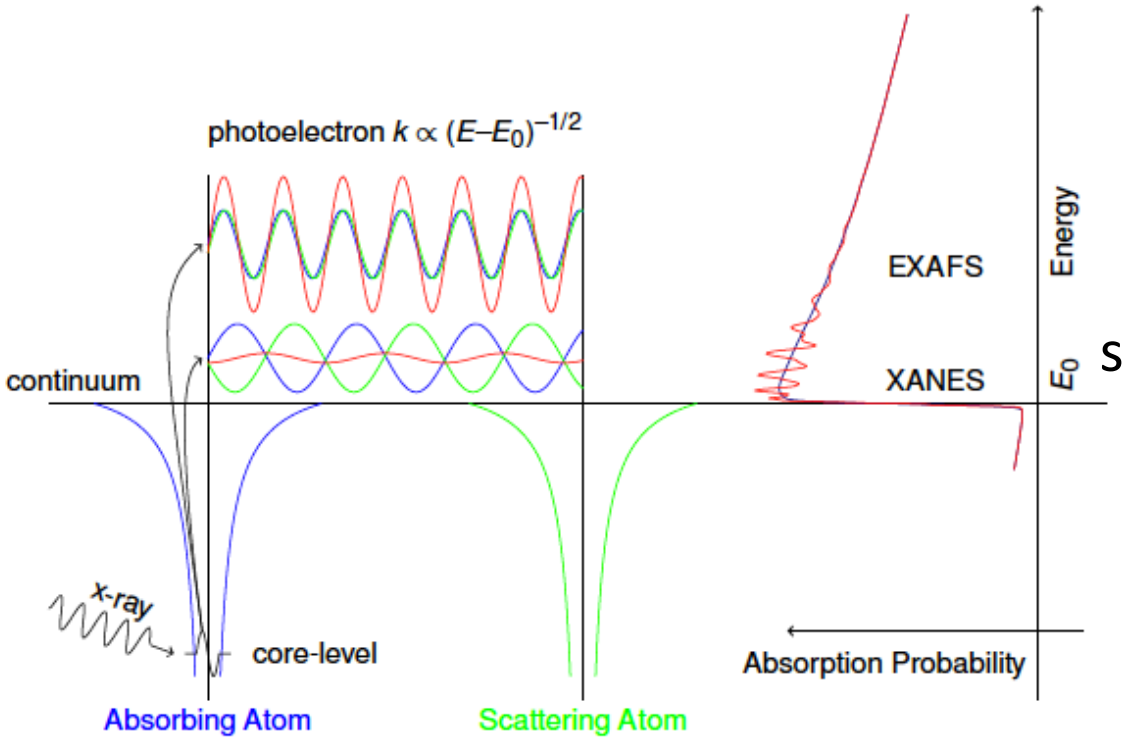


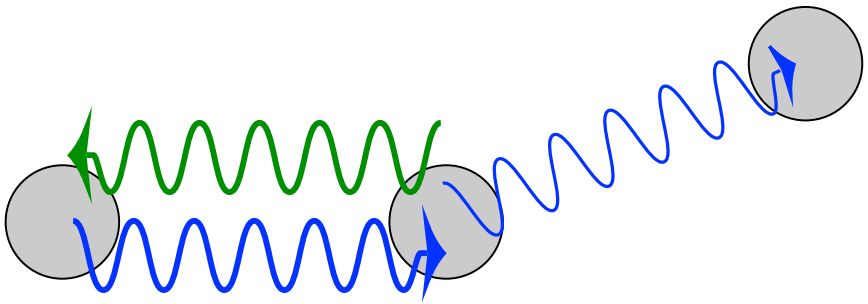
$E_{kin} = h\nu - E_B$

1s electron *K* shell

2p electron *L* shell

Picture of the wave function of final state in EXAFS





"Photoelectron (wave)" emitted

↓

scattered by the surrounding atoms

↓

Wave function of the final state pictured by "quantum theory of scattering"

Scattering of electron and interference

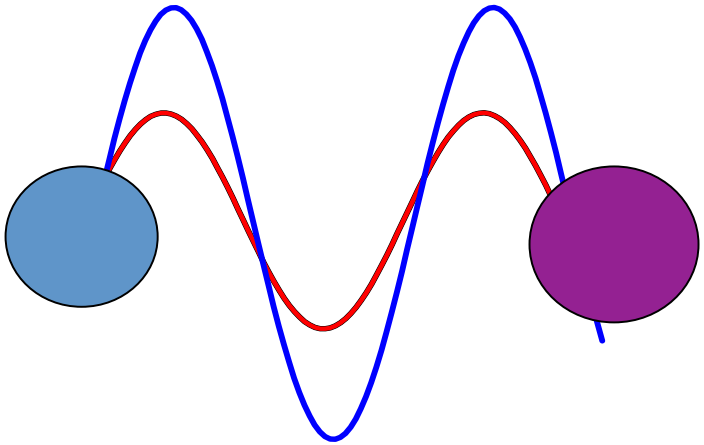
$$\frac{\hbar^2 k^2}{2m} = E - E_0$$

K : wave vector

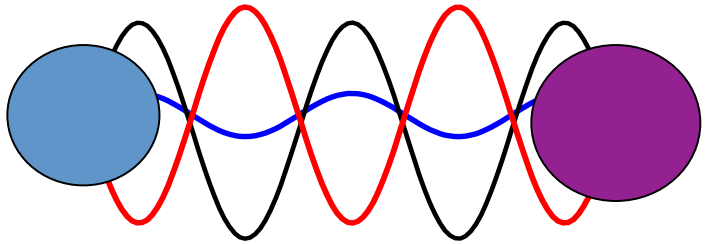
$\hbar$: Plank Const.

E : Photon energy

E_0 : threshold (edge)

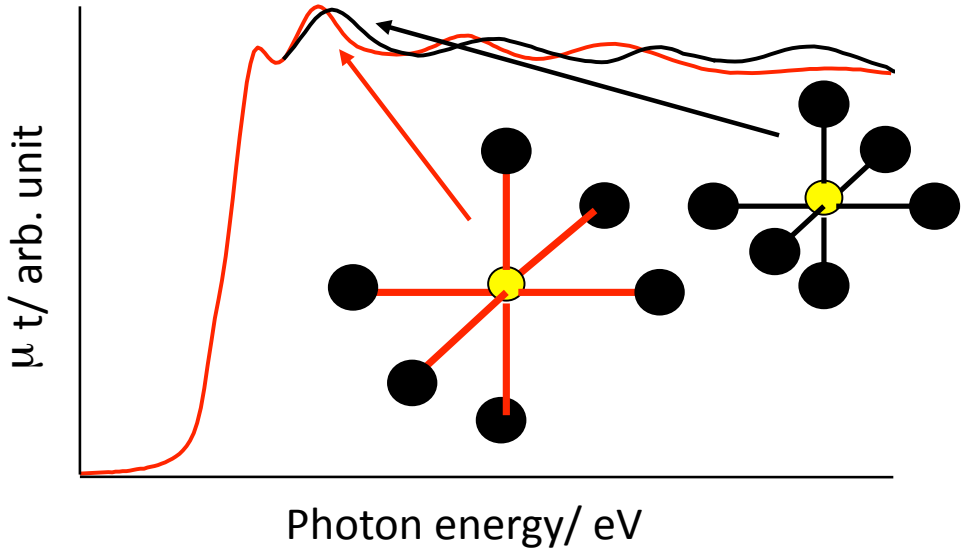


Enhancement



suppression

Bond length and Coordination number

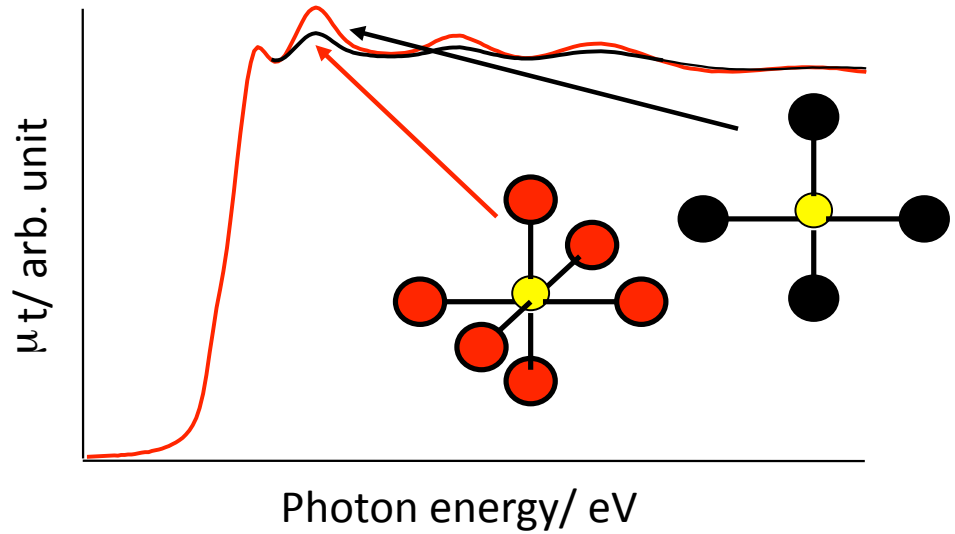


Higher frequency

(Shorter Period of Oscillation)

⇩

Longer Bond Length



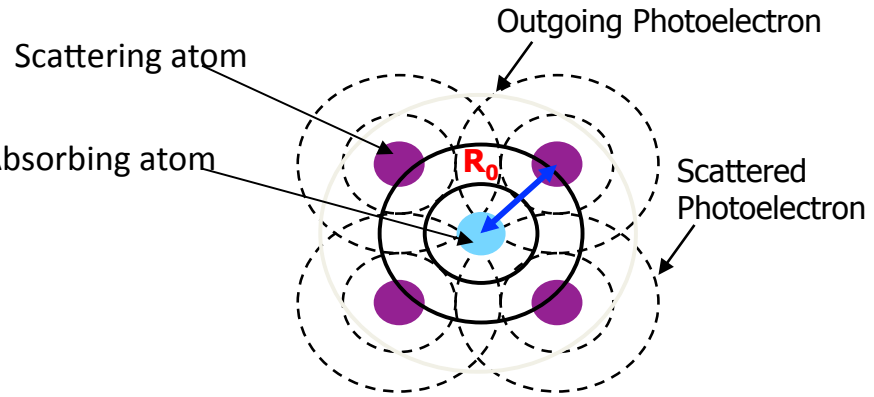
Larger Amplitude

⇩

Larger Coordination Number

The EXAFS equation

1. **leaving the absorbing atom**
2. **scattering from the neighbor atom**
3. **returning to the absorbing atom**



XAFS oscillation — Absorbance — Smooth backgroun

$$\chi(k) = \frac{\mu(E) - \mu_s(E)}{\mu_0(E)} = S_0^2 \sum_i \frac{N_i F_i(k_i)}{k_i r_i^2} e^{-2k_i^2\sigma_i^2} \sin(2k_i r_i + \phi_i(k_i))$$

Edge-jump

$$k = \sqrt{2m_e(E - E_0)/\hbar}$$

Theorptically or empirically derived Parameters

F_i : Backscattering amblitude

$* e^{-2r_i/\lambda(k_i)}$

ϕ_i : Phase shift

Curve-Fitting Parameters

N_i Coordination number

σ_i^2 DWfactor

E_0 energy shift

r distance

Fermi's Golden Rule to express μ of XAFS

Born-Oppenheimer approximation

velocity of nuclear motion << that of electronic motion

(due to the high ratio between nuclear and electronic masses)

Time-dependent Perturbation theory

Fermi's Golden Rule

$$\mu \propto \sum_f \left| \left\langle \Psi_f \left| H' \right| \Psi_i \right\rangle \right|^2 \delta\left(E_f - E_i - \hbar\omega\right) \quad \text{...(1)}$$

$$H' = -\frac{e}{mc} A(r) \cdot P$$

$A(r)$: vector potential of X-ray

P: momentum of electron

$$A(r) = \hat{e} A_0 e^{ik \cdot r}$$

$\hat{e}$: unit vector of electric field

r: position of electron

k: wave number vector of X-ray

One-electron approx. & Dipole approx.

$$\mu \propto \sum_f \left| \left\langle \Psi_f \left| H' \right| \Psi_i \right\rangle \right|^2 \delta\left(E_f - E_i - \hbar\omega\right) \quad \text{...(1)}$$

One-electron approx.: $\left\langle \Psi_f \left| H' \right| \Psi_i \right\rangle \cong \left\langle \psi_f \left| H' \right| \psi_i \right\rangle$

All-electron wave function => One-electron wave function

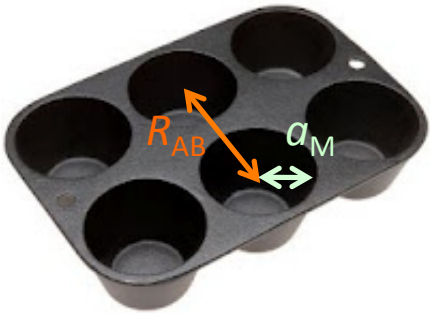
Dipole approx.: $e^{ik\cdot r} \cong 1$ for $k \cdot r << 1$

$$\mu \propto \sum_f \left| \left\langle \psi_f \left| \hat{e} \cdot r \right| \psi_i \right\rangle \right|^2 \delta\left(E_f - E_i - \hbar\omega\right) \quad \text{...(2)}$$

fundamental equation to express XAFS

Assumptions to depict EXAFS eq.

- [1] 一光子吸収
- [2] 一電子近似 & 双極子近似
- [3] (*K*殻) 電子放出 & 一電子散乱近似
- [4] $kR_{AB} >> 1$ 近似.
  - 各散乱の素過程は主要項で近似(高次項は無視できる)
- [5] Muffin-tinポテンシャル近似
  - ポテンシャルは半径a_Mの球内で球対称で、その中間領域では一定であるとする
- [6] 平面波近似.
  - 最近接原子間距離R_{AB}に対し、$a_M << R_{AB}$なので、散乱は平面波で記述できるとする



Eq. of single scattering EXAFS

Amplitude

Oscillation (phase)

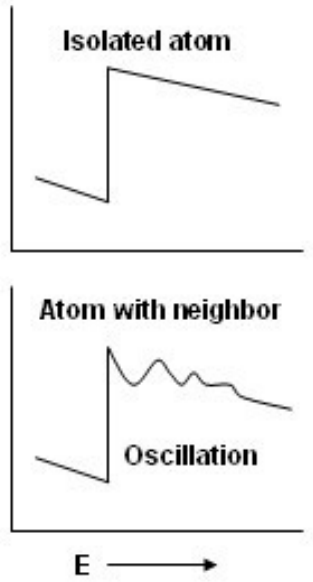
$$\chi(k) = -S_0^2 \sum_j \frac{N_j}{kR_j^2} F_j(k) \exp\left(-2\sigma_j^2 k^2\right) \sin\left(2kR_j + 2\delta_{A,1}(k) + \varphi_j(k)\right)$$

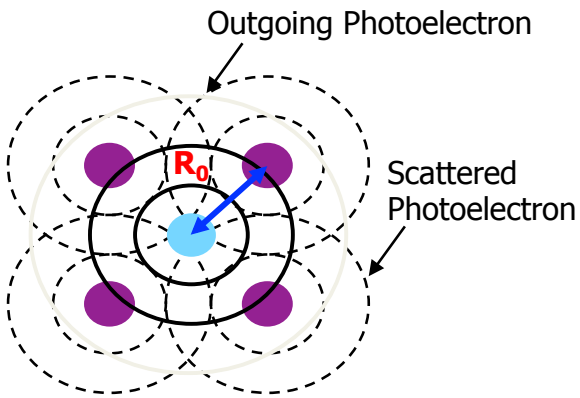
"Round trip" of the wave

Phase shift

of absorbing atom

of scattering atom





Fourier Transform…

Bond length R_j , etc.,

(Parameters high-lightened by yellow are fitting parameters.)

de Broglie wave as a Ruler

A particle with the momentum of *p*
having the wave character described by the below Eq.

as for Electron

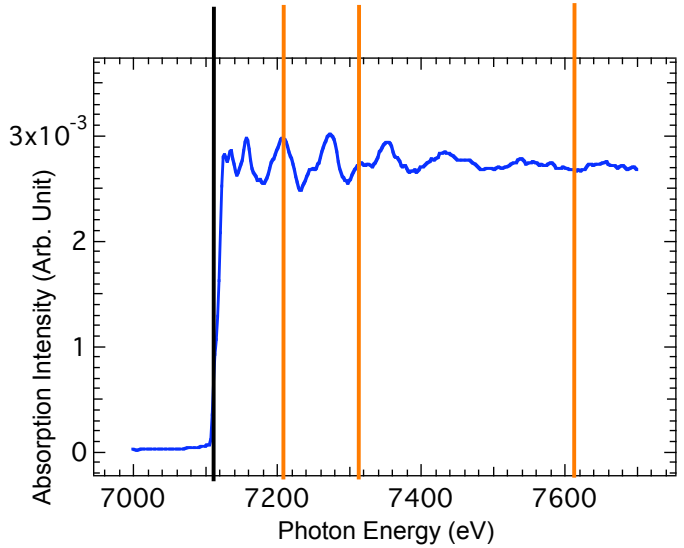
$$\lambda = \frac{h}{p} = \frac{h}{\left(2m_e eV\right)^{1/2}}$$

considering a bond length of ~2.5 Å

100 eV: 1.226 Å	2 waves
200 eV: 0.867 Å	3 waves
500 eV: 0.548 Å	4-5 waves

EXAFS

We use **de Broglie wave of electron** as a **Ruler**, in order to measure bond length

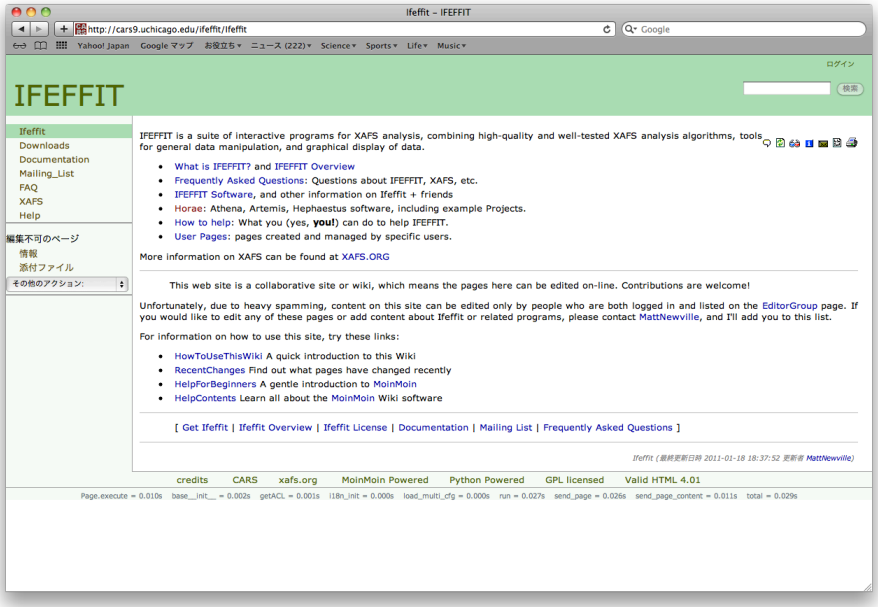


Software for XAFS analyses

Athena, Artemis (Ifeffit)

by a group at U. Chicago

http://cars9.uchicago.edu/ifeffit/Ifeffit



REX2000

by RIGAKU corp.

http://www.rigaku.co.jp/products/p/xdxa0020/

Of course, there are many other softwares, and you can use what you'd like to.

2004G332

XRF + XANES study

Arsenic distribution and speciation in an arsenic hyperaccumulator fern by X-ray spectrometry utilizing a synchrotron radiation source

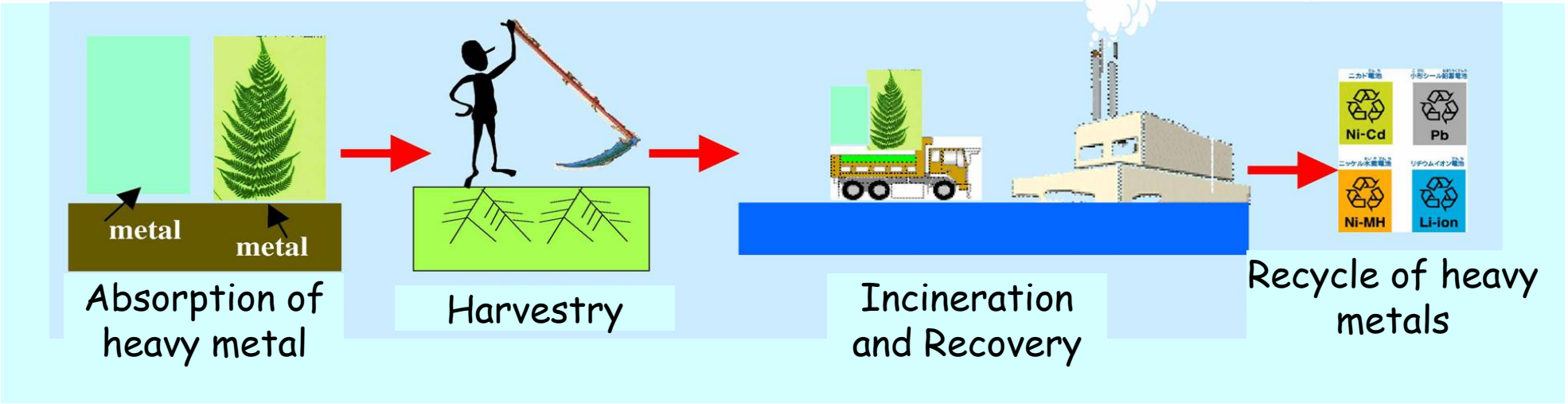
Akiko Hokura, Ryoko Omuma, Yasuko Terada, Nobuyuki Kitajima, Tomoko Abe, Hiroyuki Saito, Shigeo Yoshida and Izumi Nakai

Journal of Analytical Atomic Spectrometry, 2006, DOI: 10.1039/b512792k

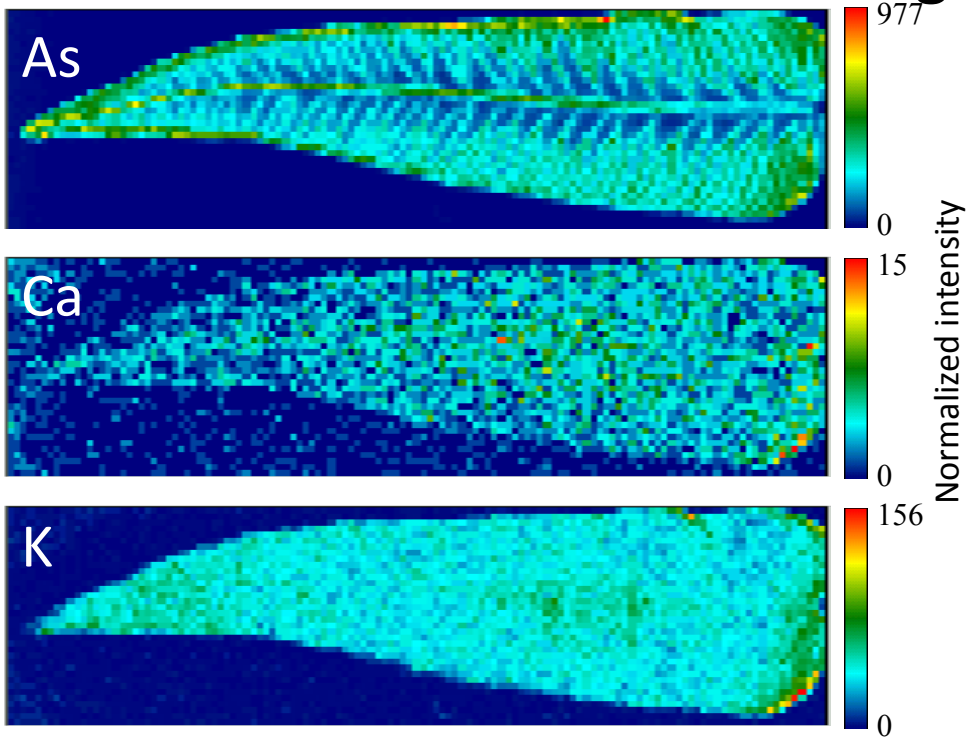
Arsenic hyper accumulator: Chinese brake fern (*Pteris vittata* L.)

It contains large amounts of arsenic (As: *ca.* 22,000 μg g^{-1} dry weight) when grown on contaminated soil (L.Q. Ma, et al., *Nature* 2001).

Phytoremediation: Remediation of environment by using plant



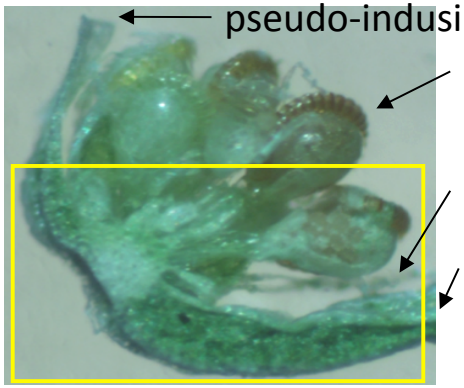
Elemental distribution in fern's pinna obtained by XRF imaging

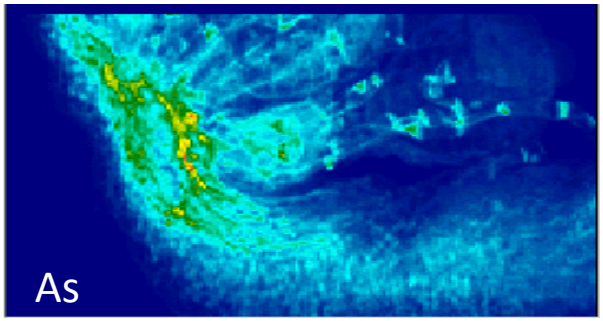


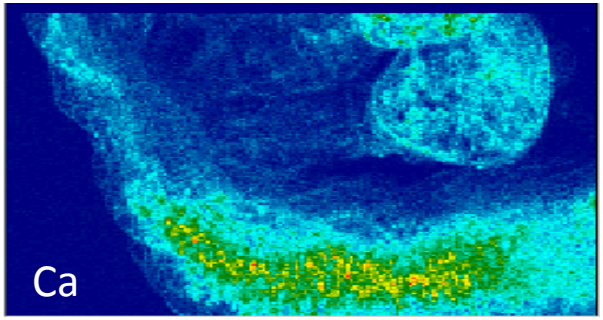
X-ray Energy : 16.5 keV
Step number : 125 points × 36 points
Measurement time : 3 s/point

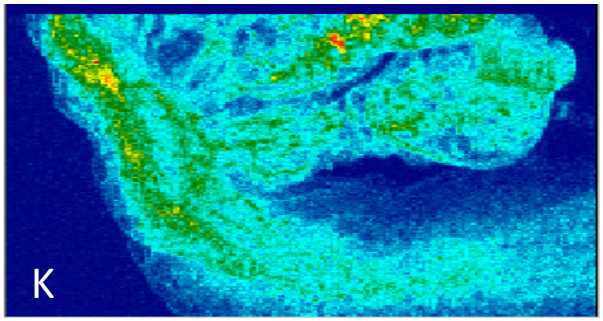
SR facility	BL-4A, PF, KEK
Storage ring, Current range	2.5 GeV, 300-420 mA
Monochromator	Si (111) double crystal
Focusing optics	Spherical mirror coated with Rh for vertical focusing
Beam size	200 μm x 200 μm
Detector	Si(Li) SSD detector
Atmosphere	Air

Elemental distribution obtained by μ-XRF imaging







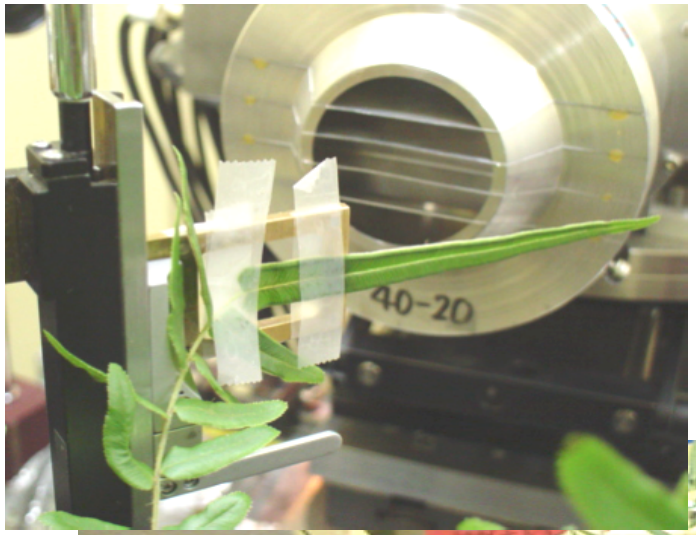


High levels of arsenic accumulate at the base of sporangium with lamina of pinnae

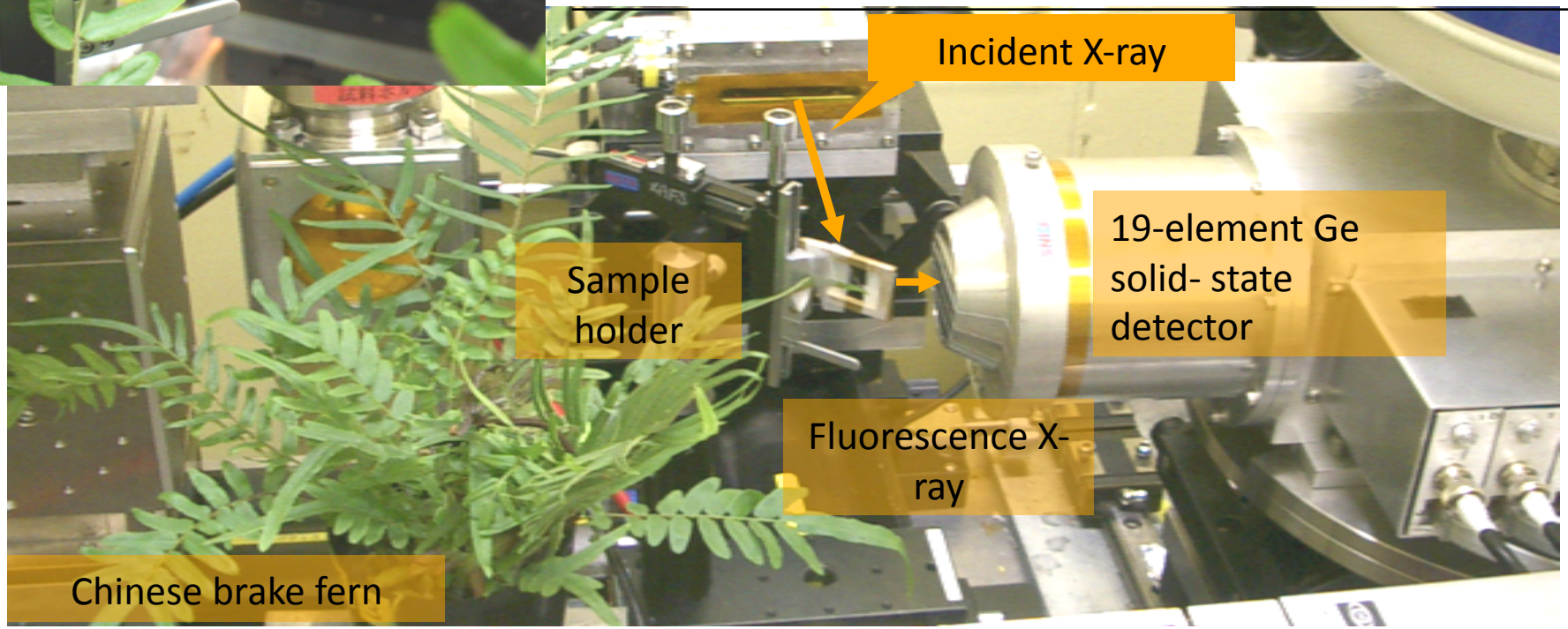
SR facility	BL-4A, PF, KEK
Monochromator	W/B4C double multilayer
Focusing optics	K-B mirror coated with Rh
Beam size	3.5 μm x 5.5 μm
Detector	Si(Li) SSD detector
Atmosphere	Air

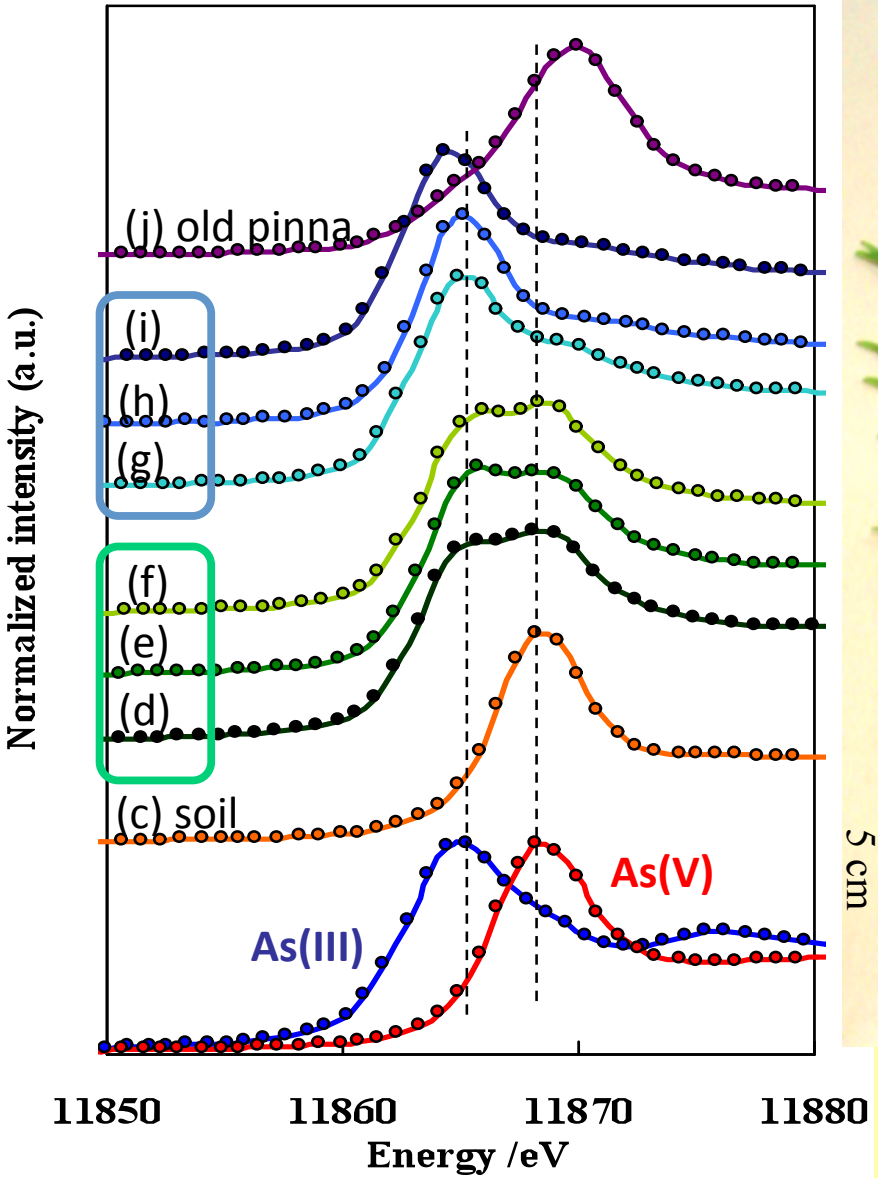
X-ray Energy : 14.2 keV
Step number : 180 points × 125 points
Measurement time : 1 s/point

in vivo As K-edge XANES analysis

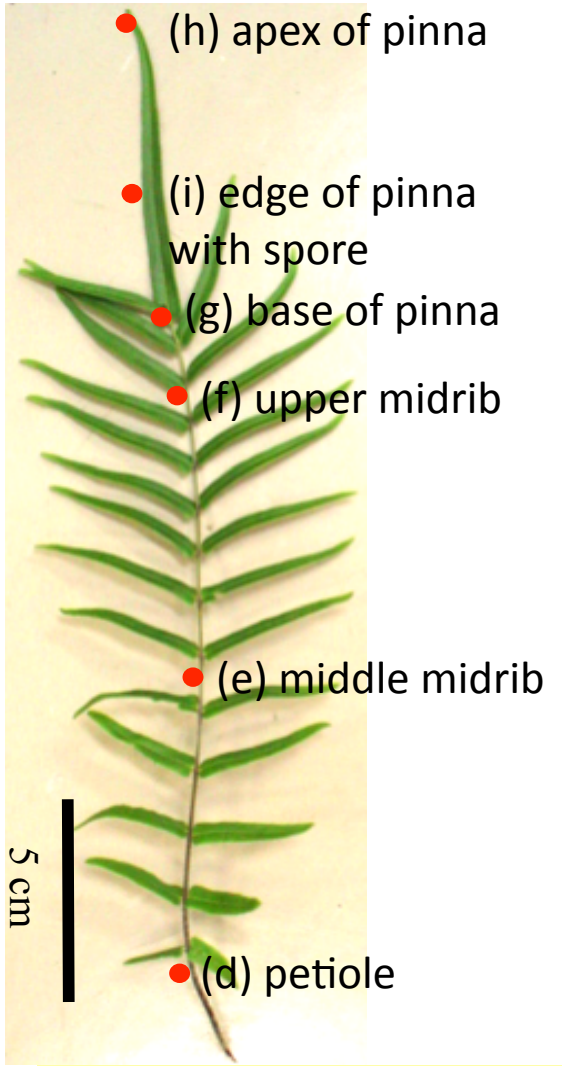


SR facility	BL-12C, PF, KEK
Storage ring	2.5 GeV
Current range	300-420 mA
Monochromator	Si (111) double crystal
Focusing mirror	Bent cylindrical mirror
Beam size	*ca.* 1 mm x 1 mm
Fluorescence X-ray detector	19-element Ge solid-state detector
Atmosphere	Air





As K edge XANES spectra of Chinese brake fern.



As(III) in pinna

Both As(V) and As(III) exist in the petiole and midrib

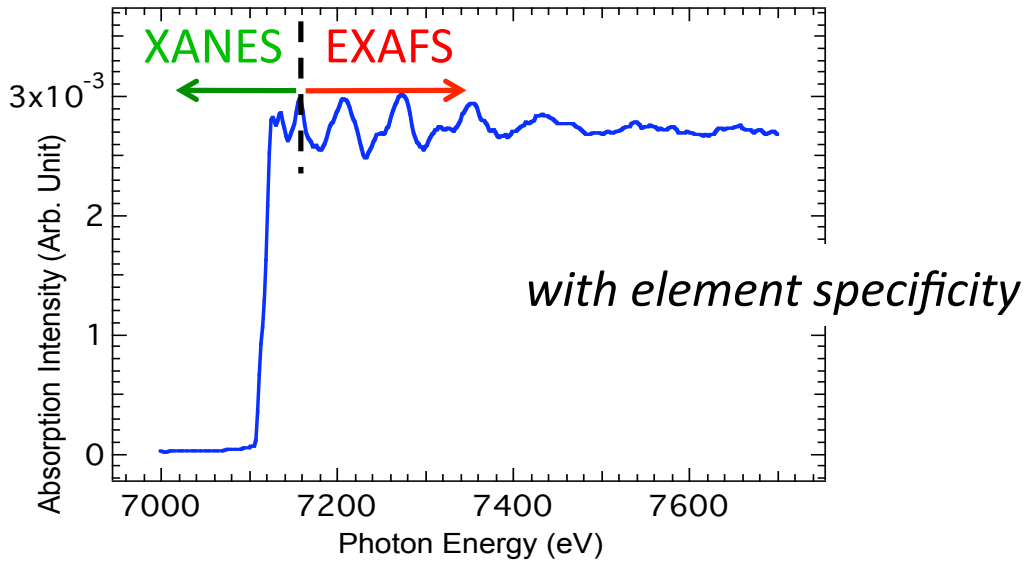
	As(III)	As(V)
(f)	66%	34%
(e)	71%	29%
(d)	63%	37%

The fern uptakes arsenic as As(V) from soil and the As (V) is then partially reduced to As(III) within the plant.
The arsenic finally accumulating as As(III) in a specific area of the pinna.

Take-home massage

XAFS : XANES + EXAFS

- XANES gives us...
  - Valence state
  - Symmetry



with element specificity

- EXAFS gives us...
  - Bond length
    - **A local structure** is given.
    - **Crystallinity, or long range order is not required**.
  - Coordination number (CN)
    - Simply, the number of atoms around the atom.
    - CN enables us to estimate sizes of nano clusters.

The ruler is de Broglie wave of electron!!